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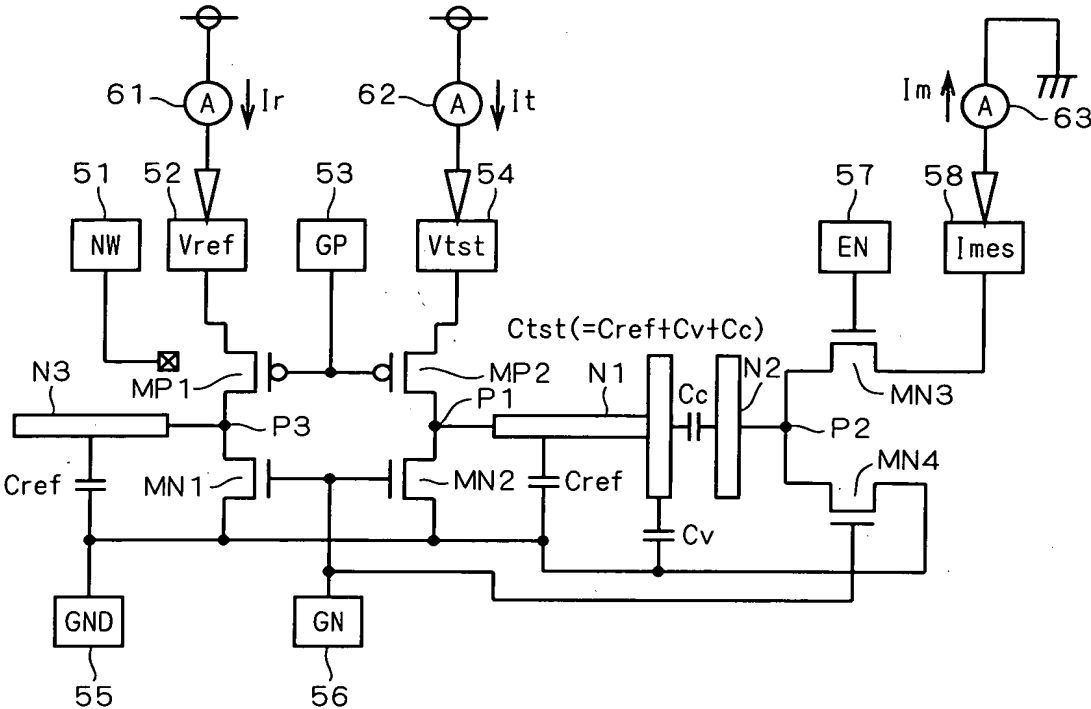
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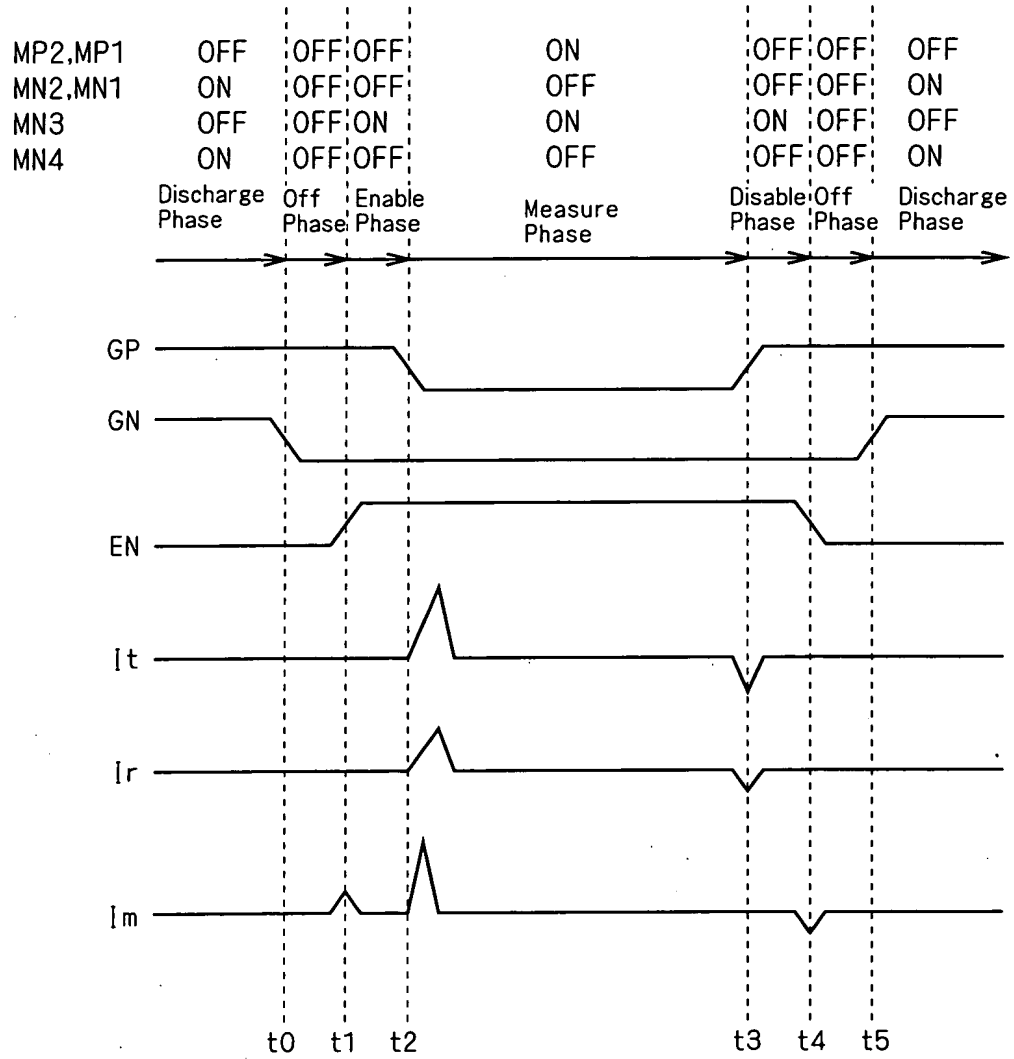
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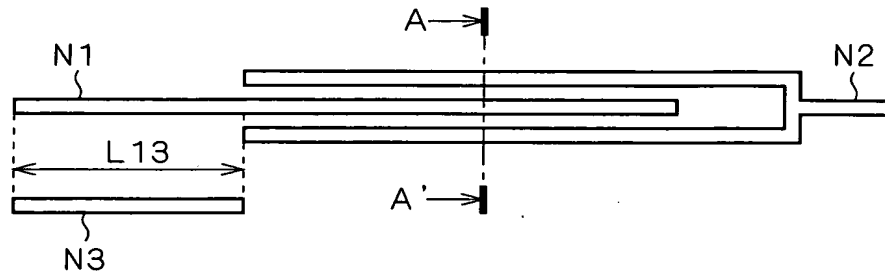
F I G . 1



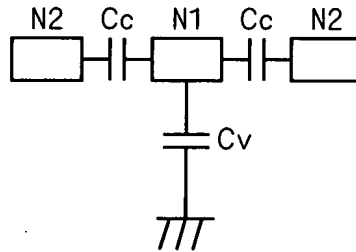
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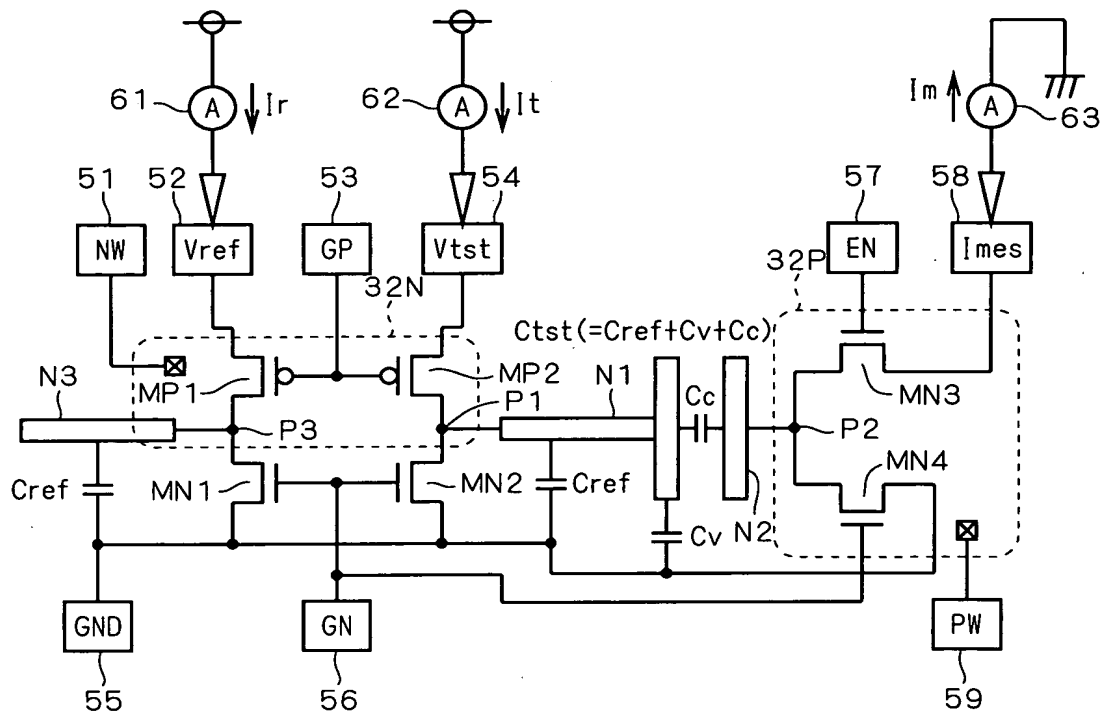
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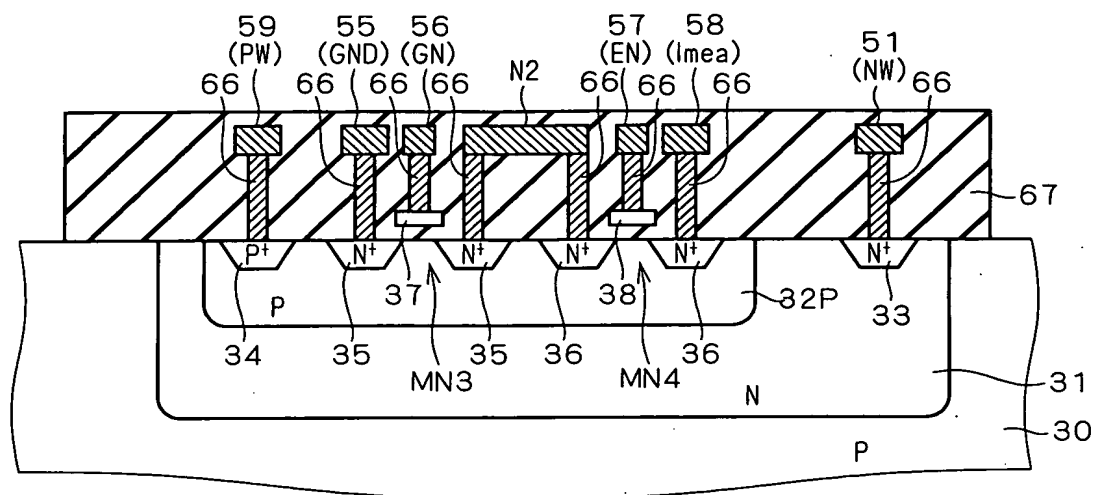
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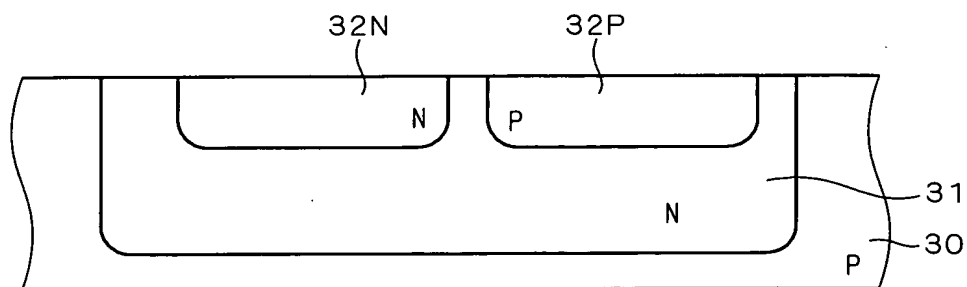
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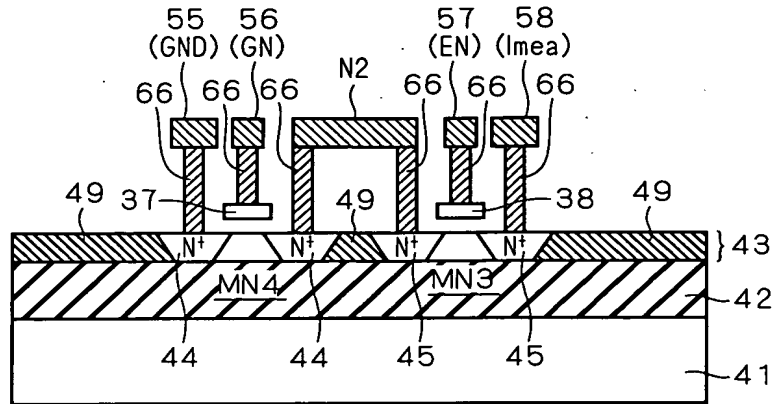
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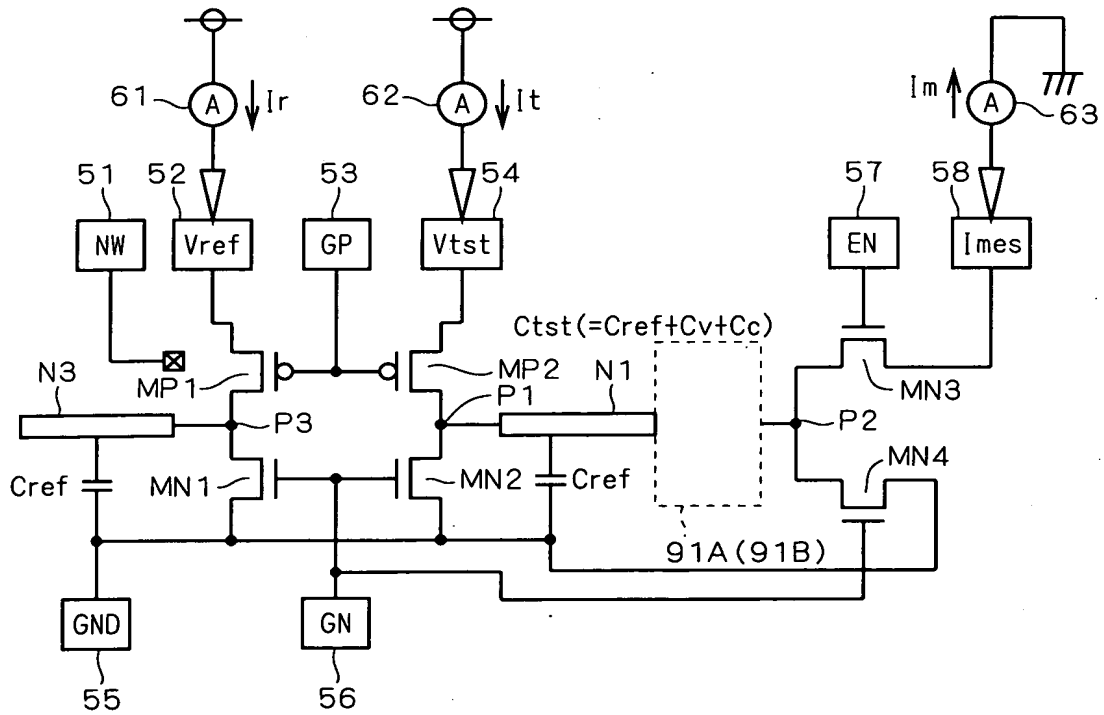
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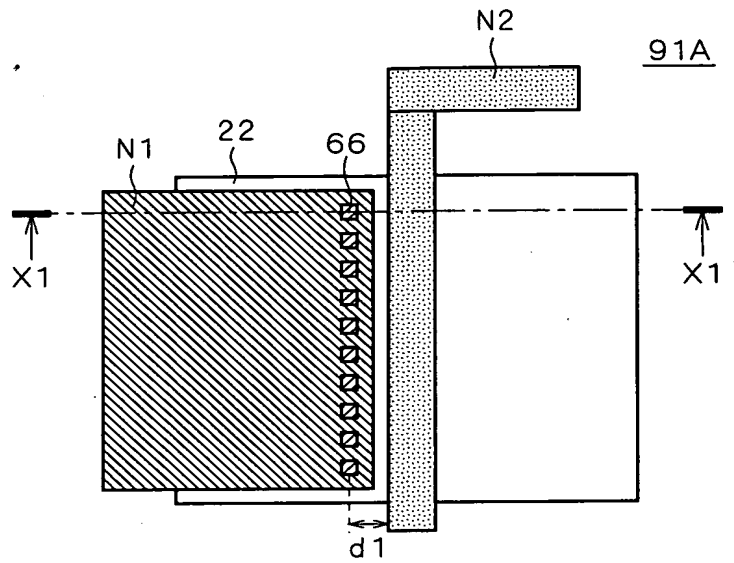
F I G . 8



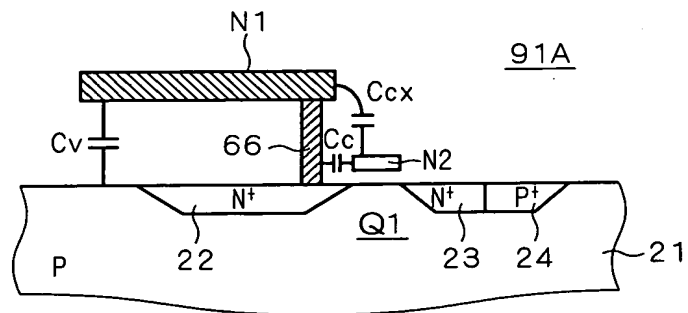
F I G . 9



F I G . 1 0

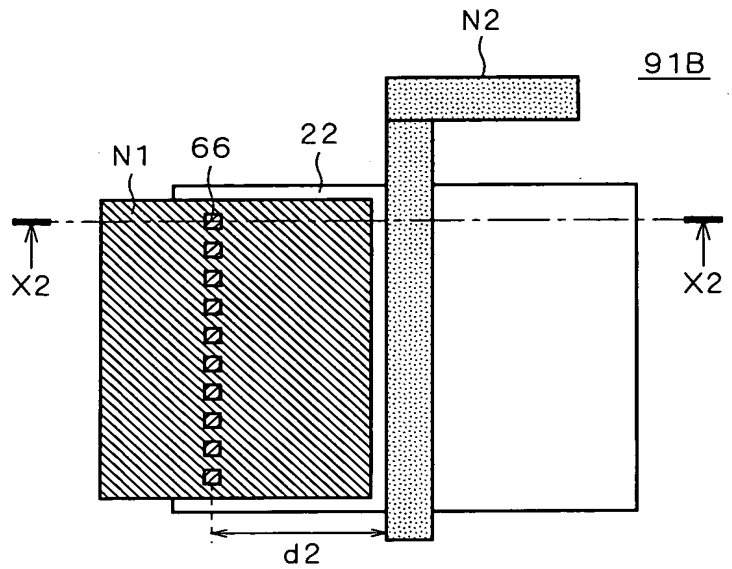


F I G . 1 1

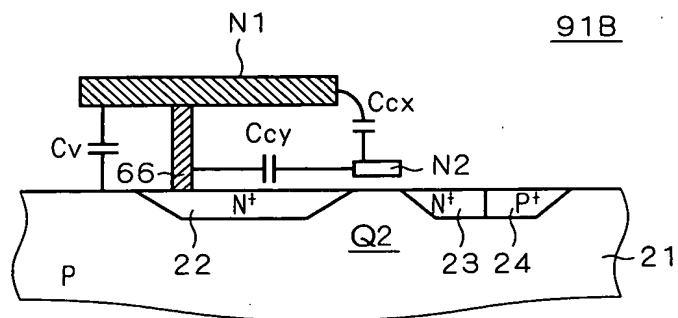




F I G . 1 2

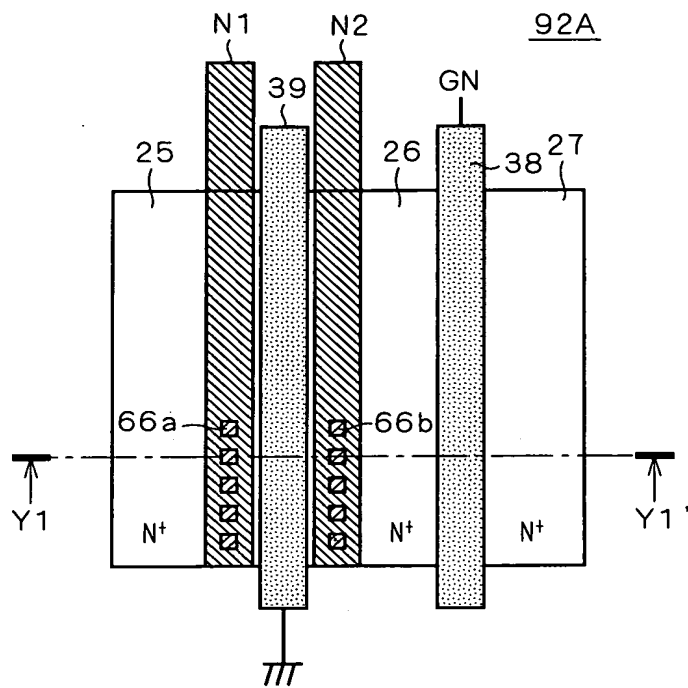


F I G . 1 3

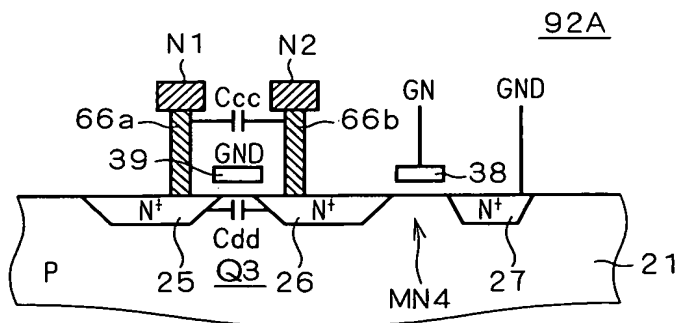




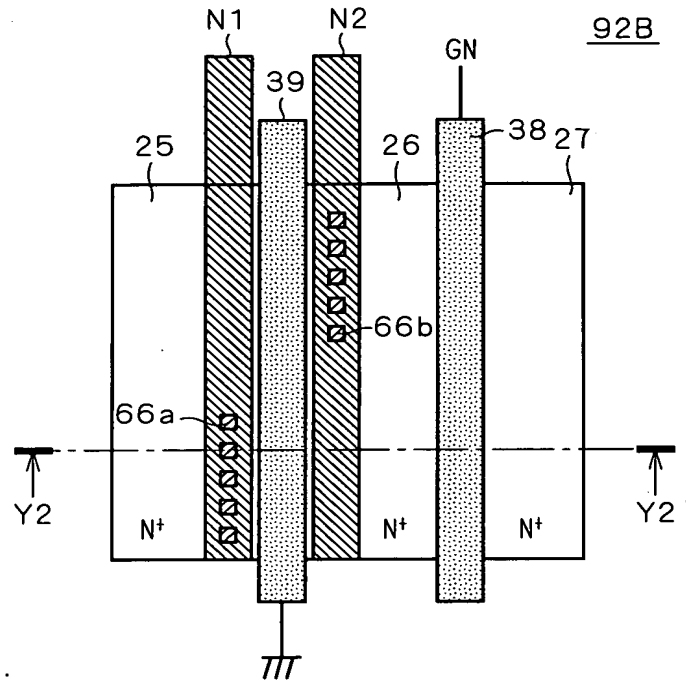
F I G . 1 5

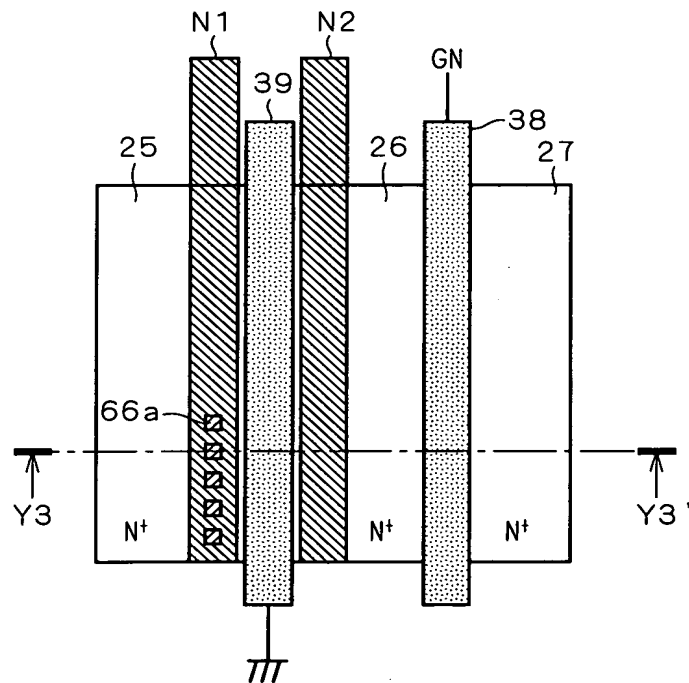


F I G . 1 6



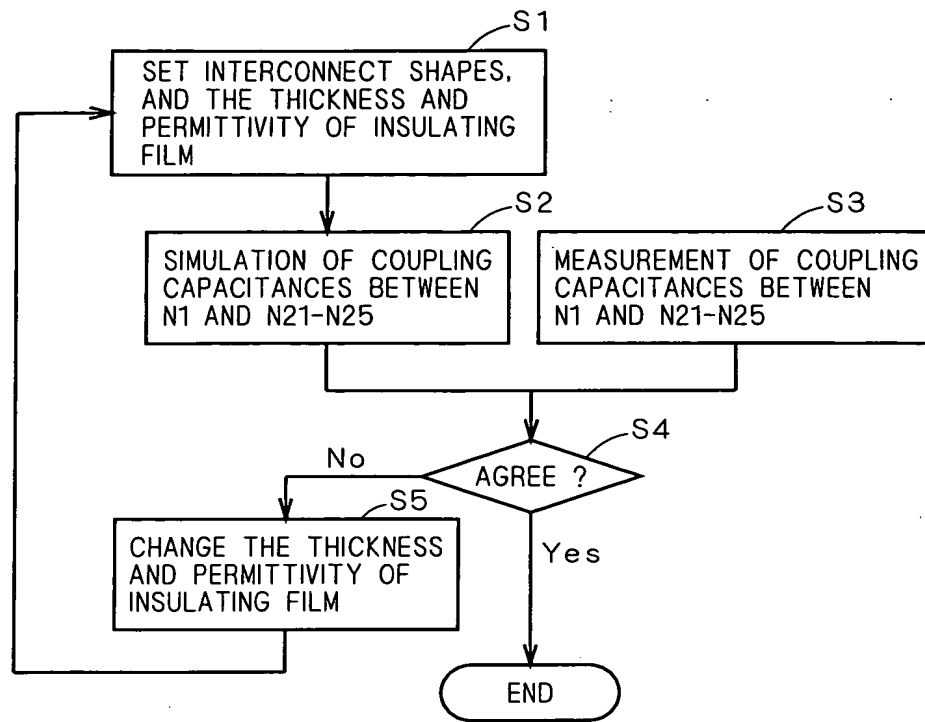
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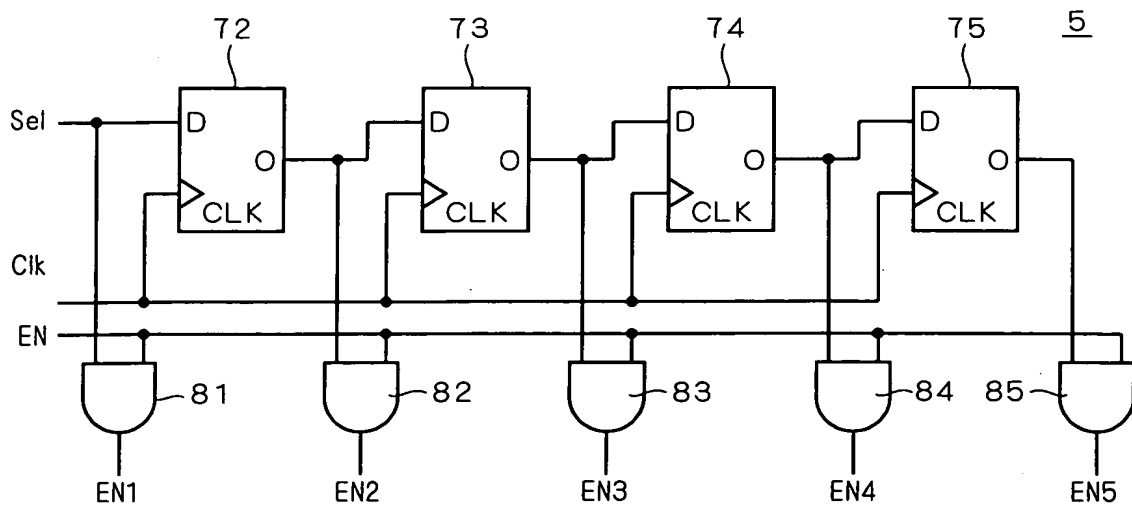




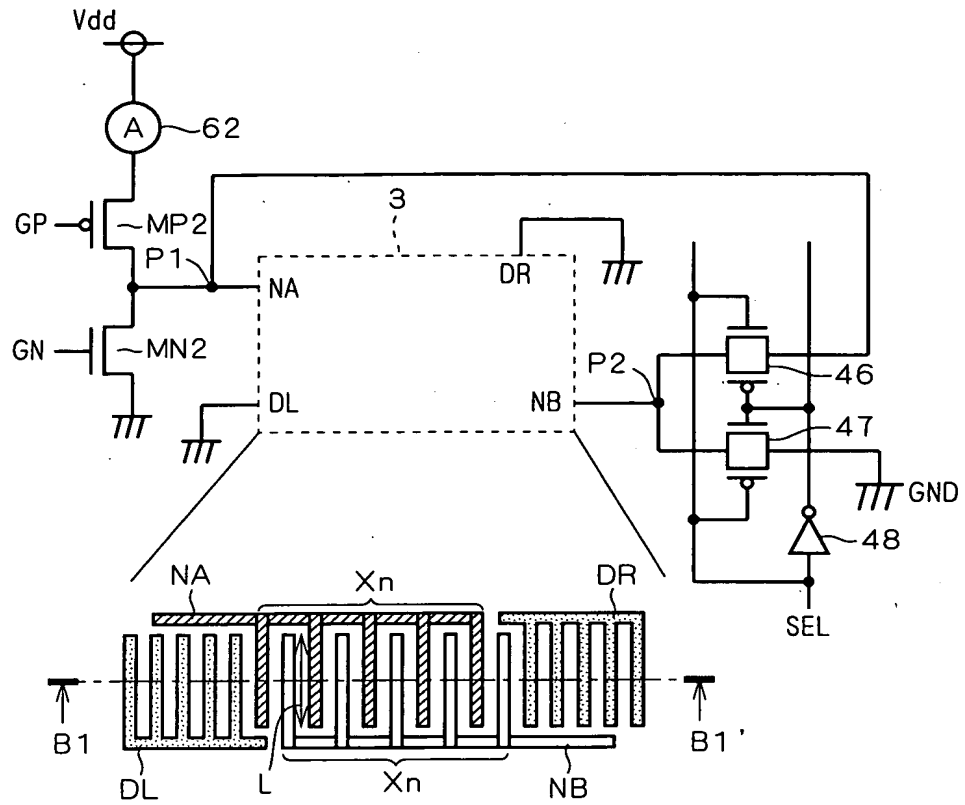
F I G . 2 3



F I G . 2 4

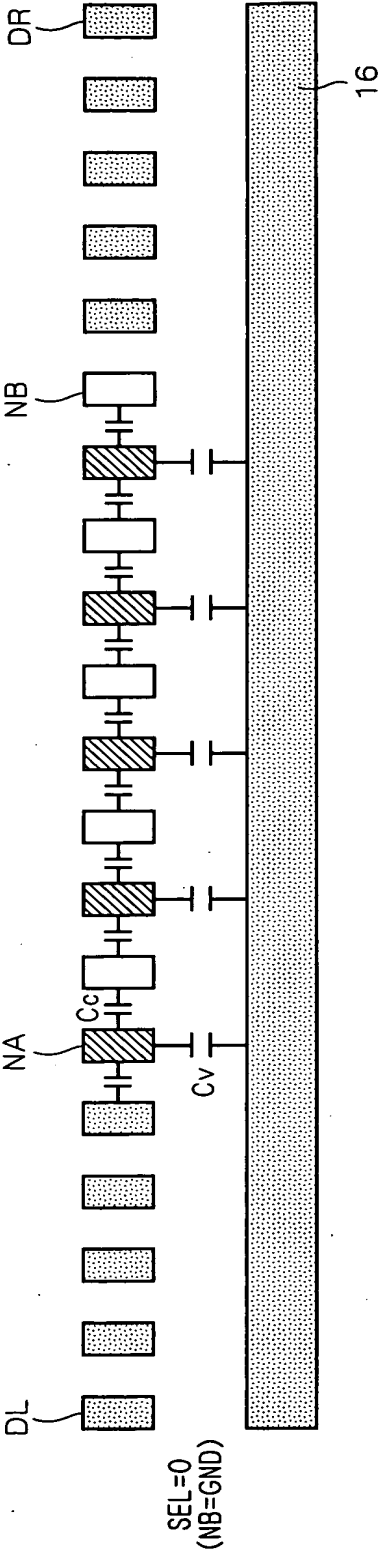


F I G . 2 5

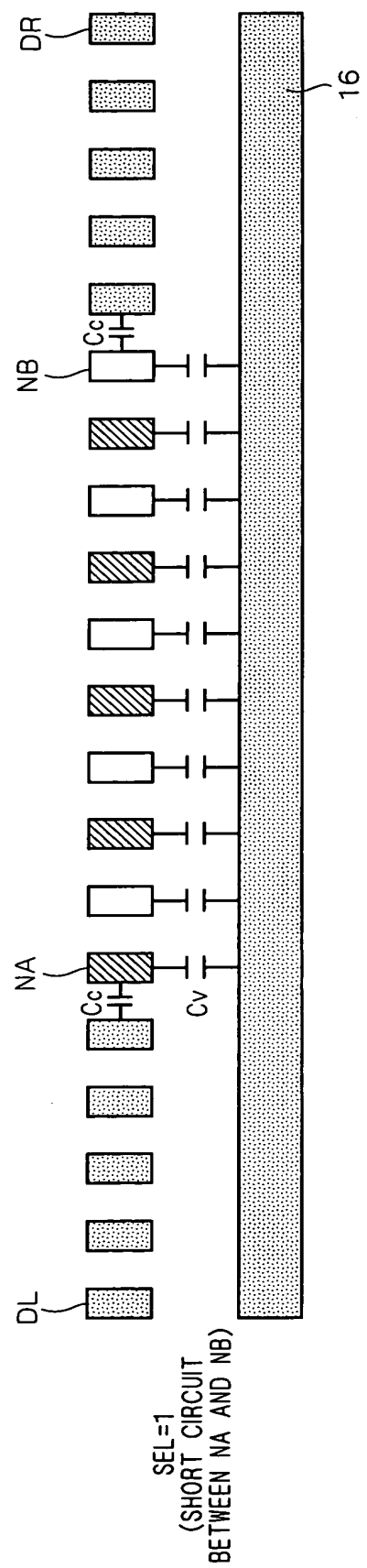




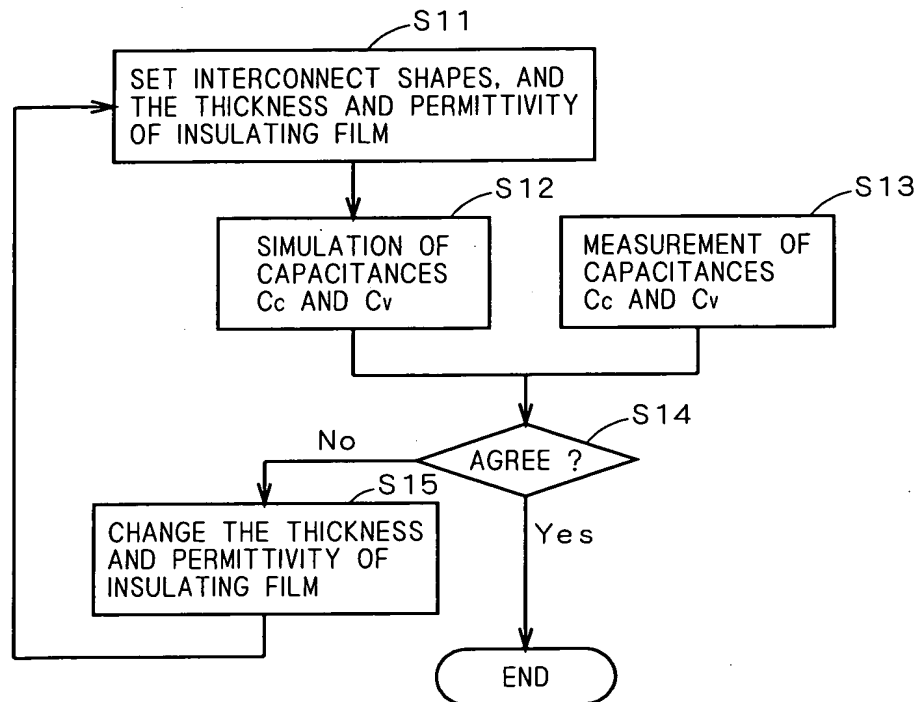
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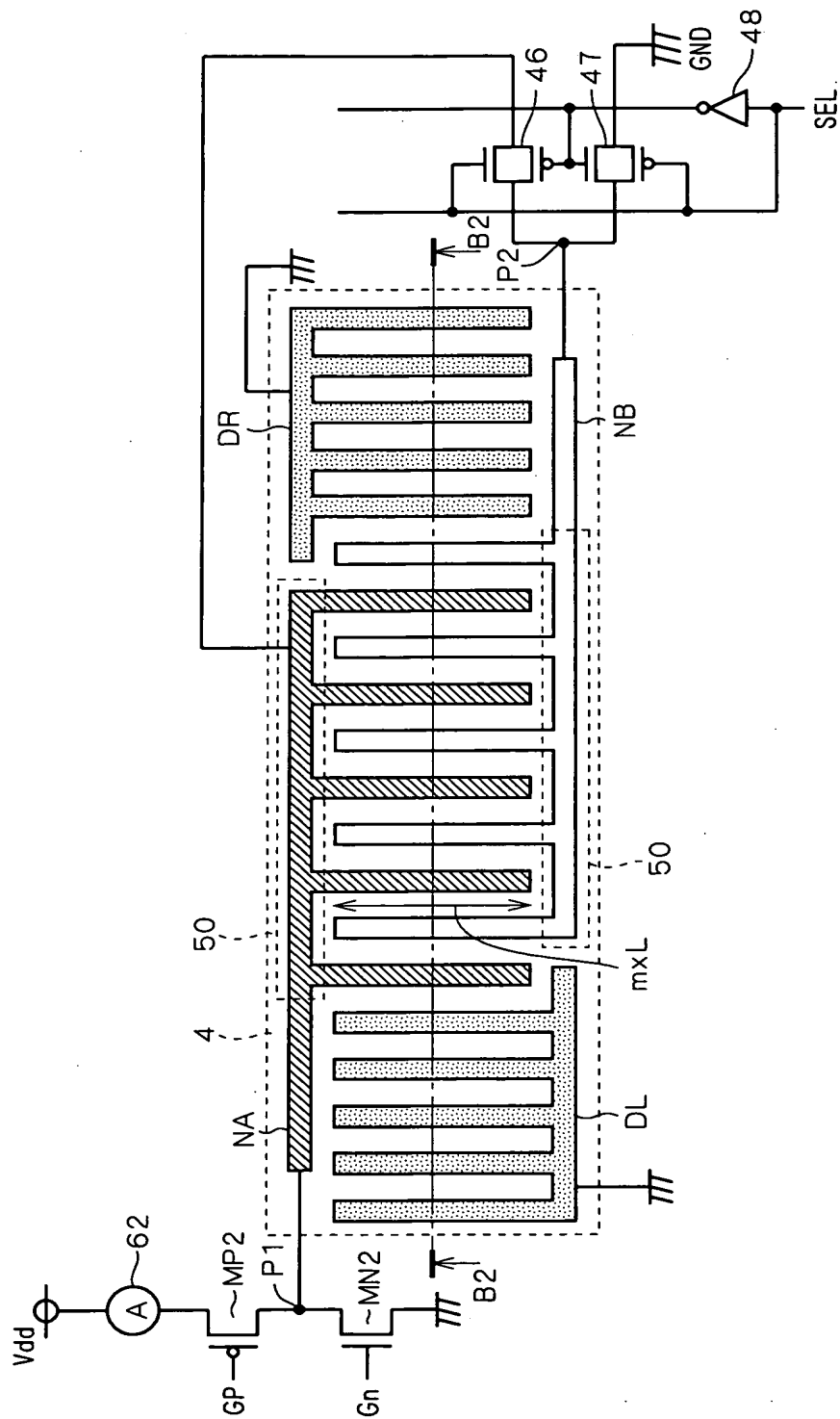


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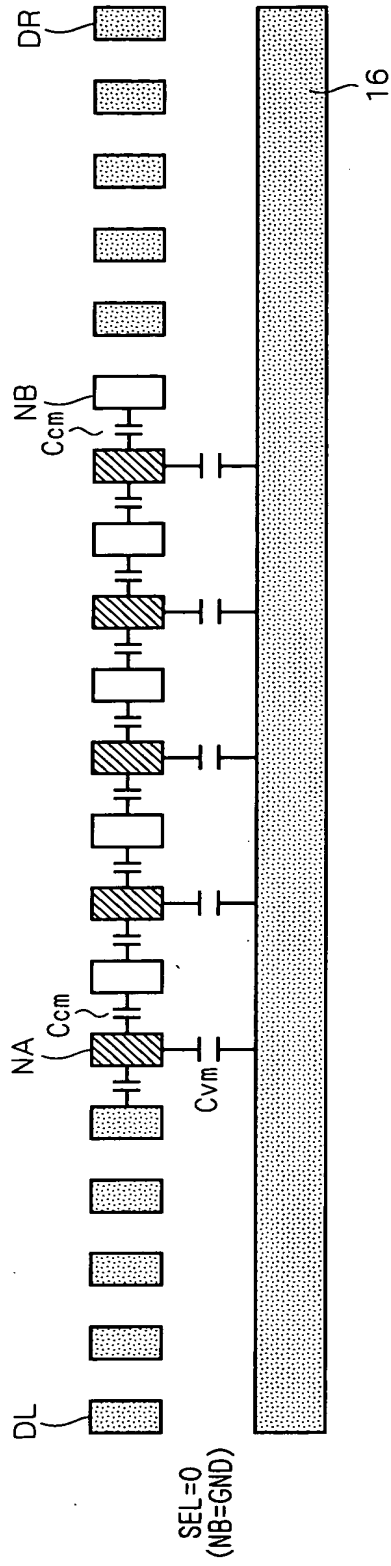


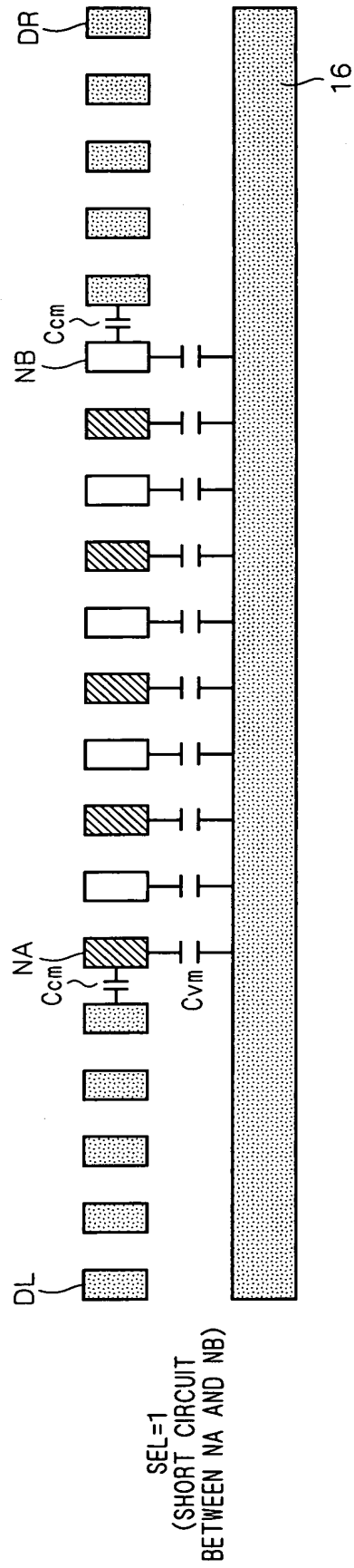
F I G . 2 8



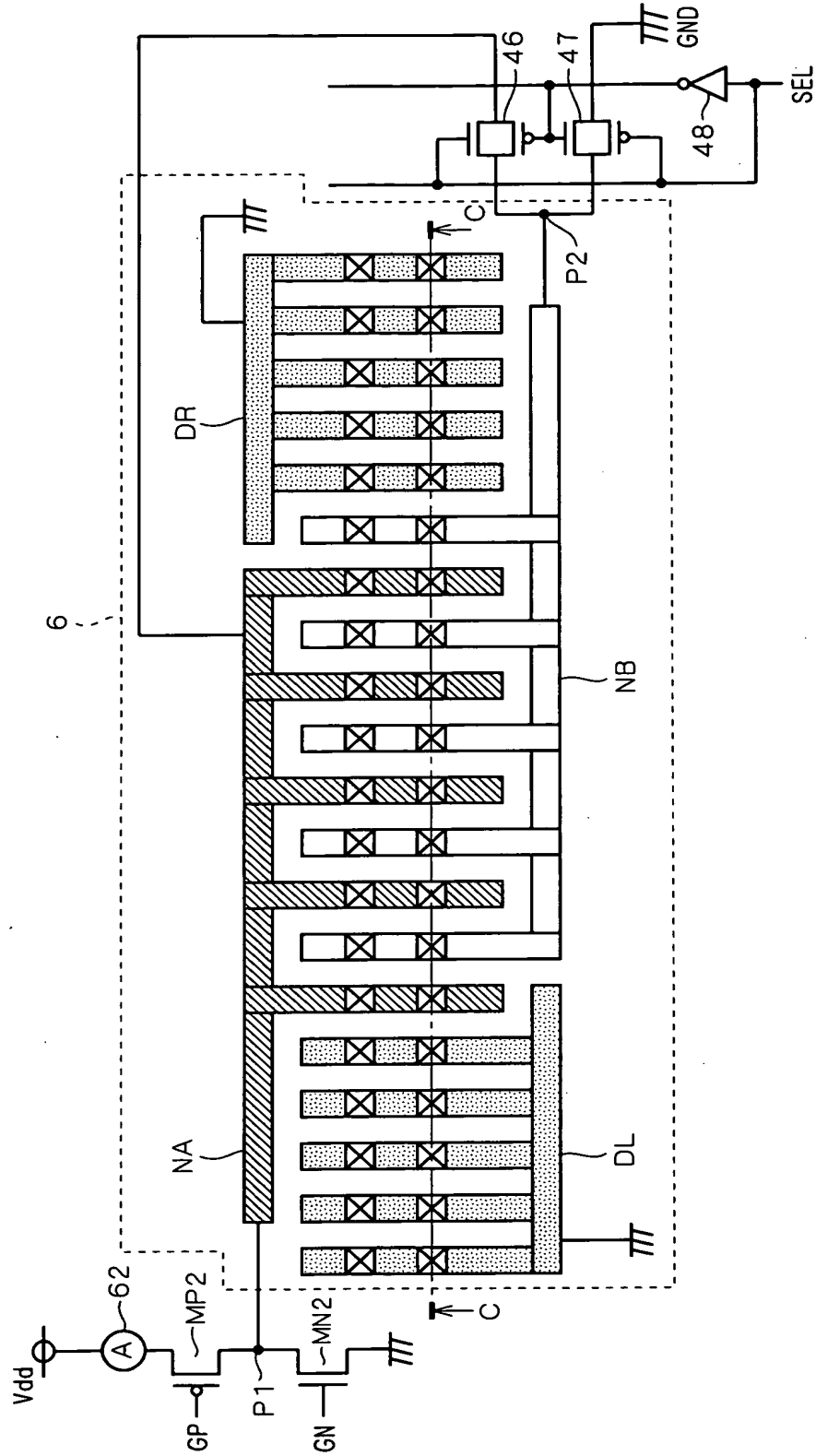


F I G . 3 0



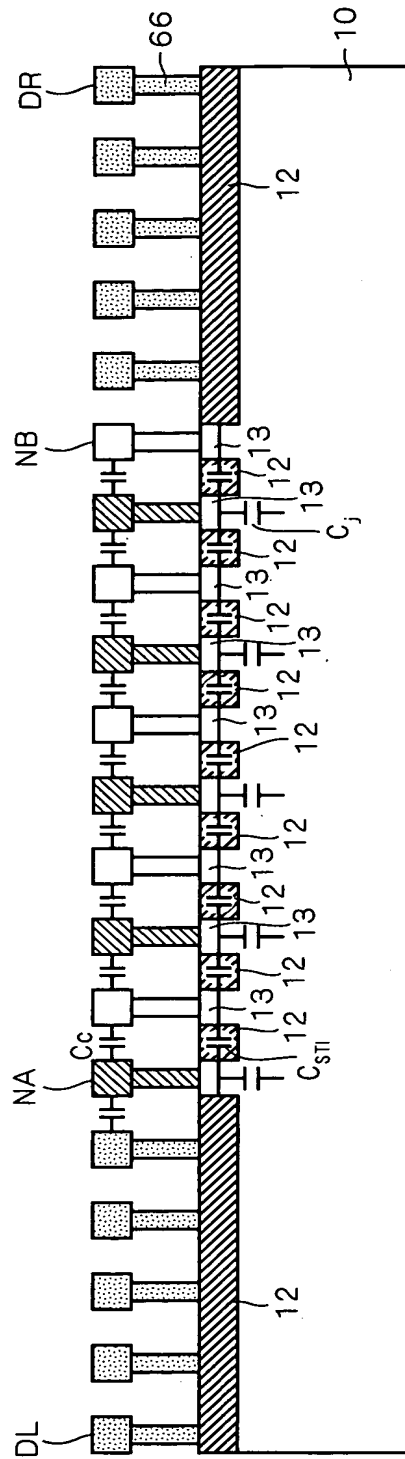


F I G . 3 2



F I G . 3 3

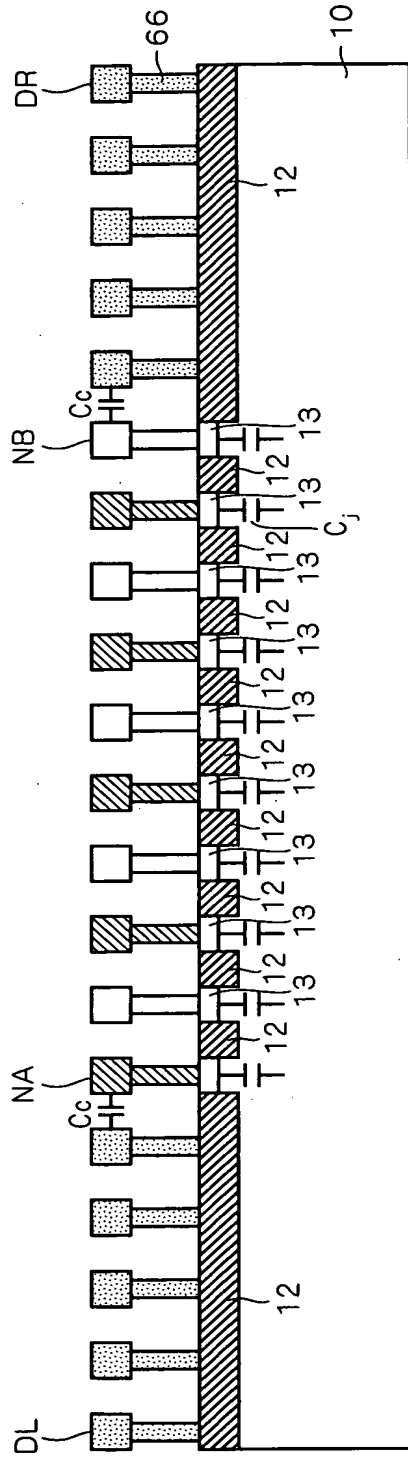
SEL=0  
(NB=GND)

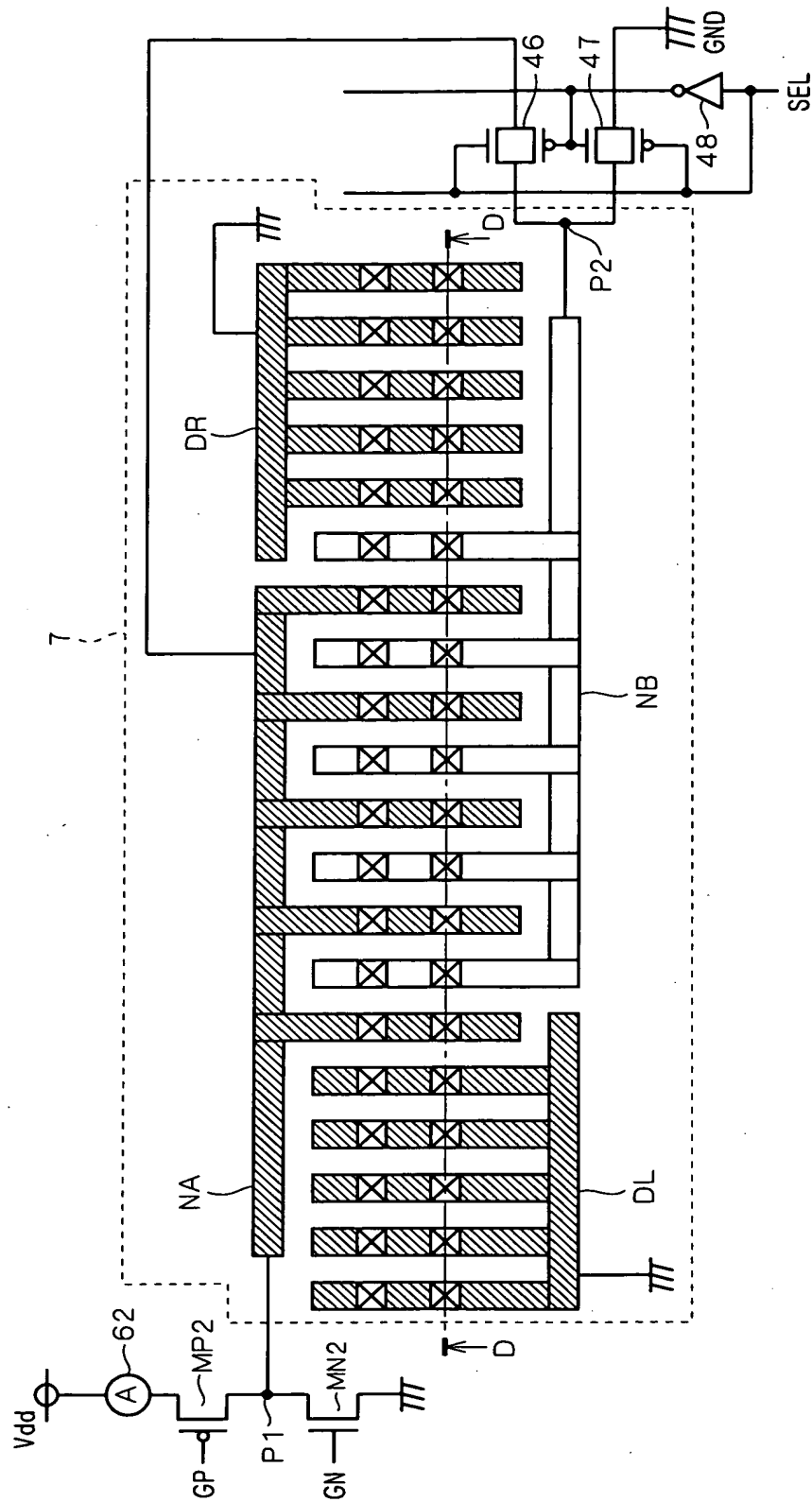




F I G . 3 4

SEL=1  
(NB=NB)





F I G . 3 6

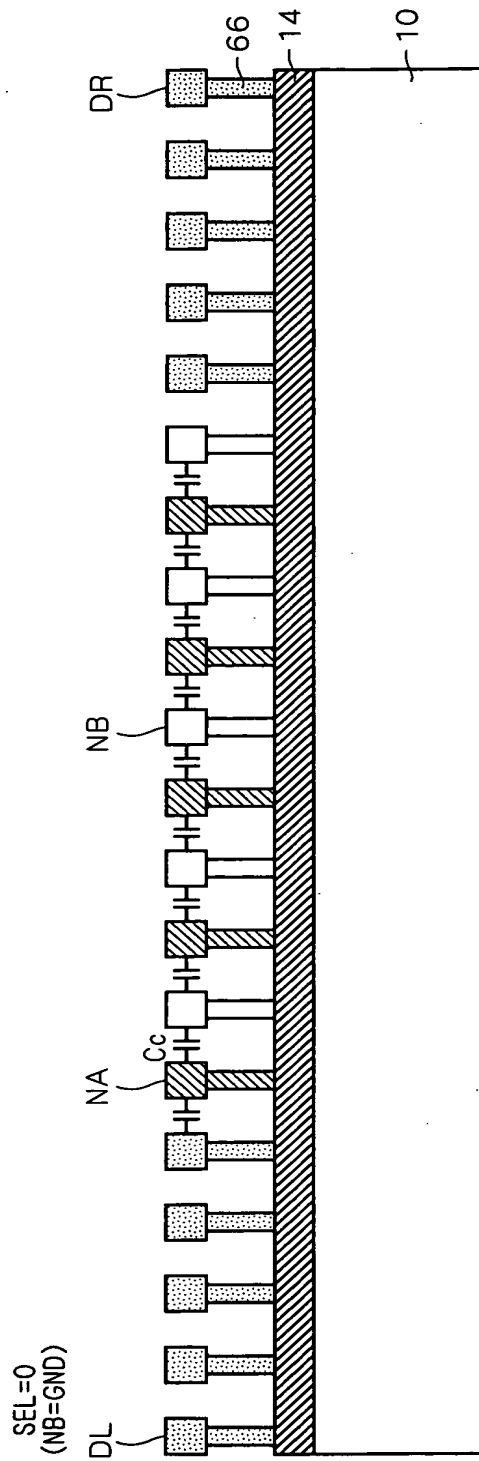
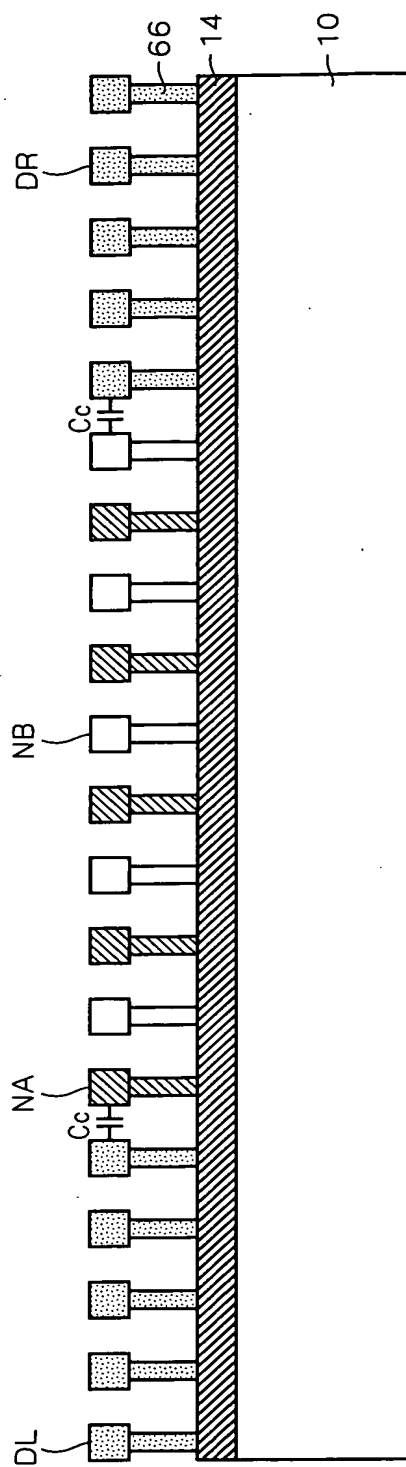


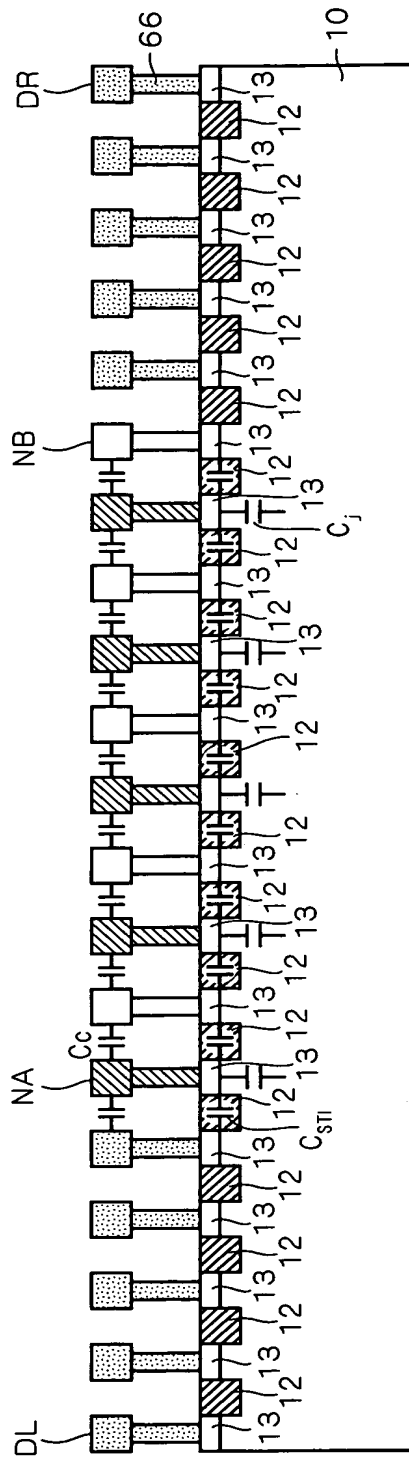
FIG. 7.3

**SEL=1  
(NA=NB)**



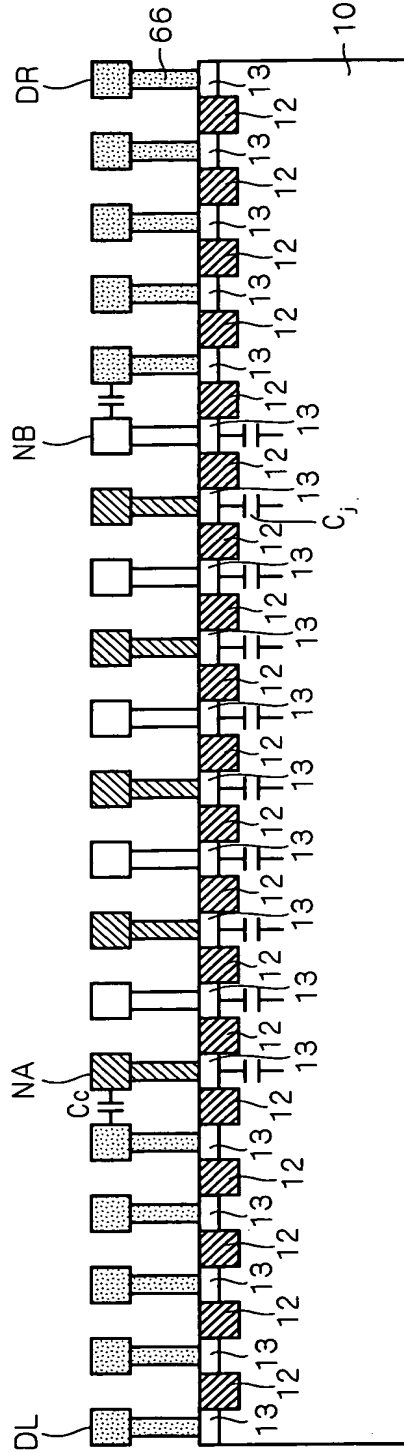
F I G . 3 8

SEL=0  
(NB=GND)



F I G . 3 9

SEL=1  
(NB=NB)



F I G . 4 0

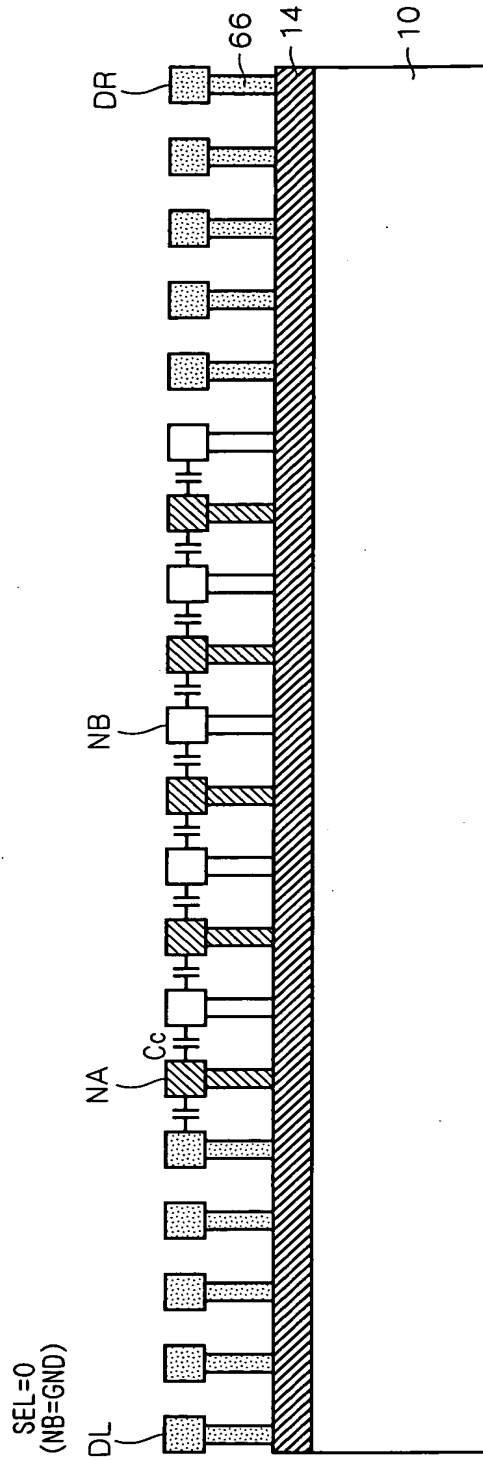
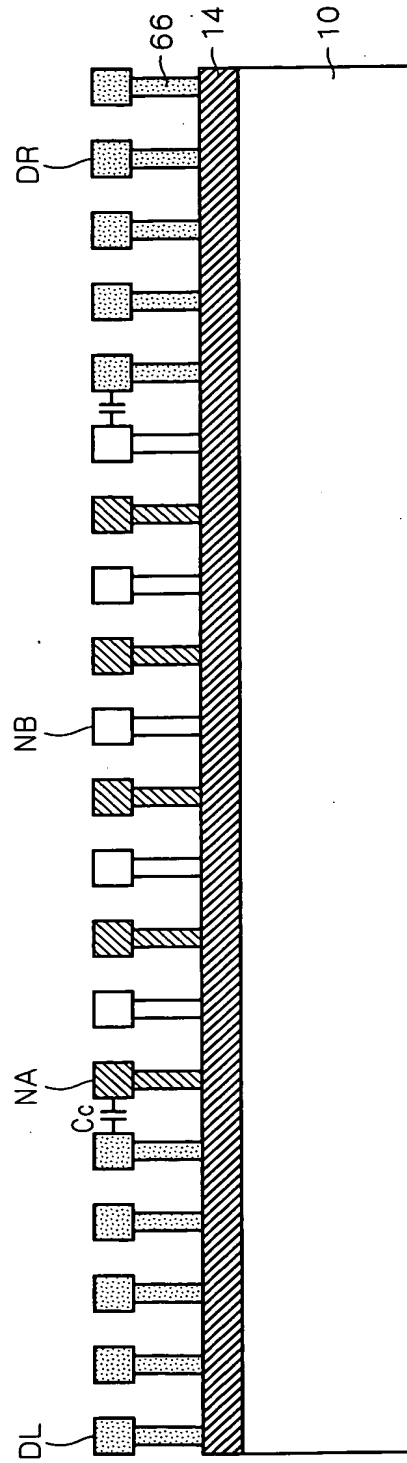


FIG. 41

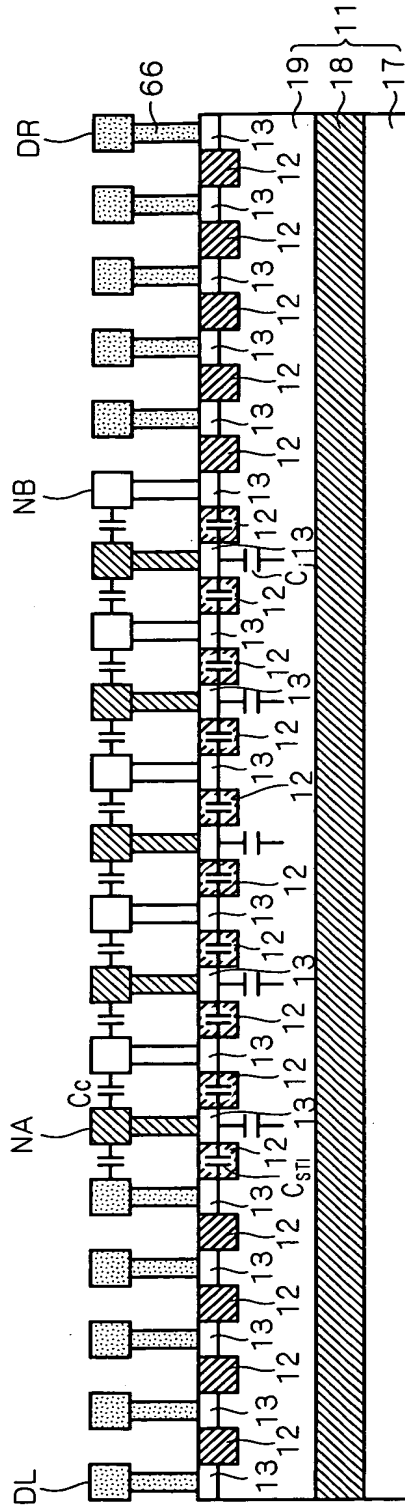
SEL=1  
(NB=NB)





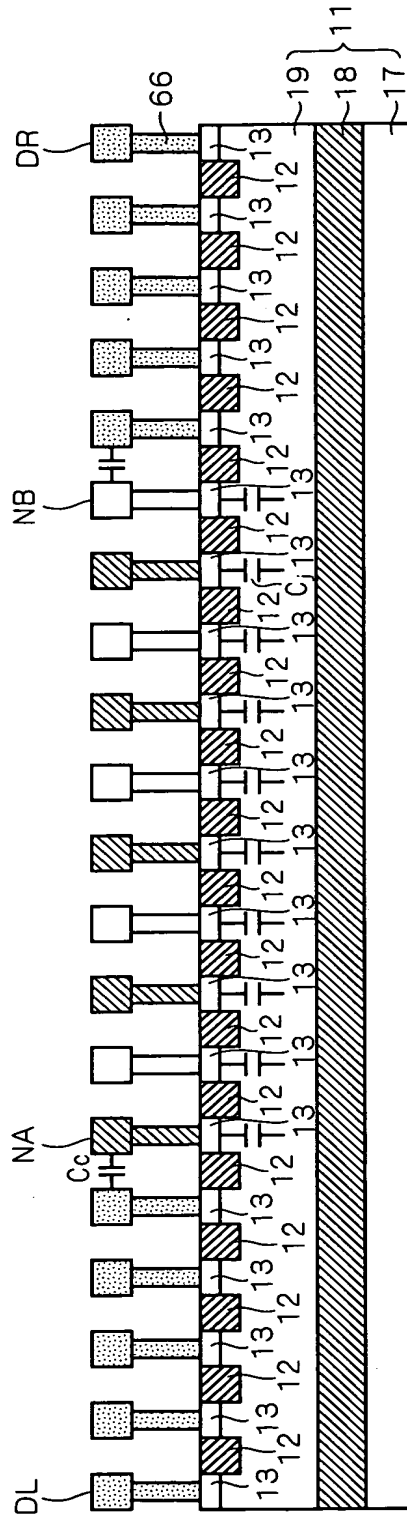
F I G . 4 2

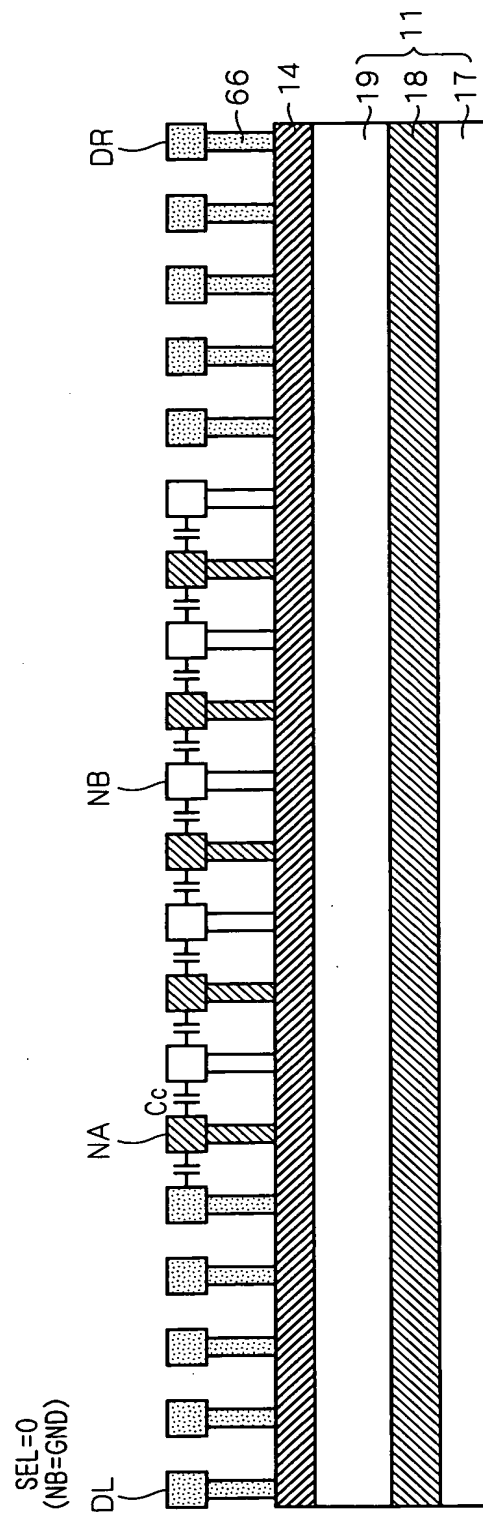
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(NB=GND)



F I G . 4 3

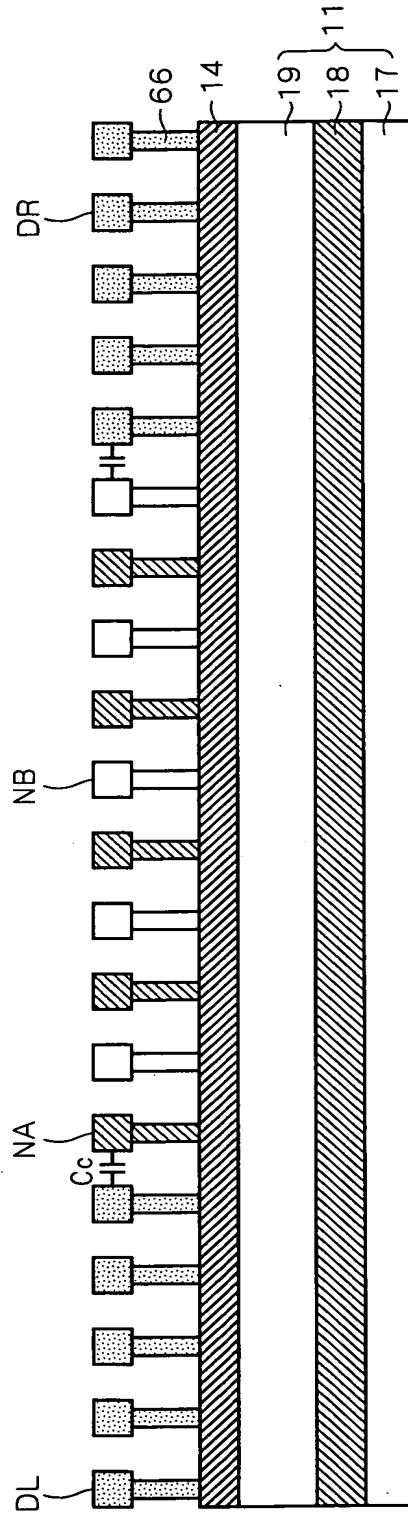
SEL=1  
(NB=NB)





F I G . 4 5

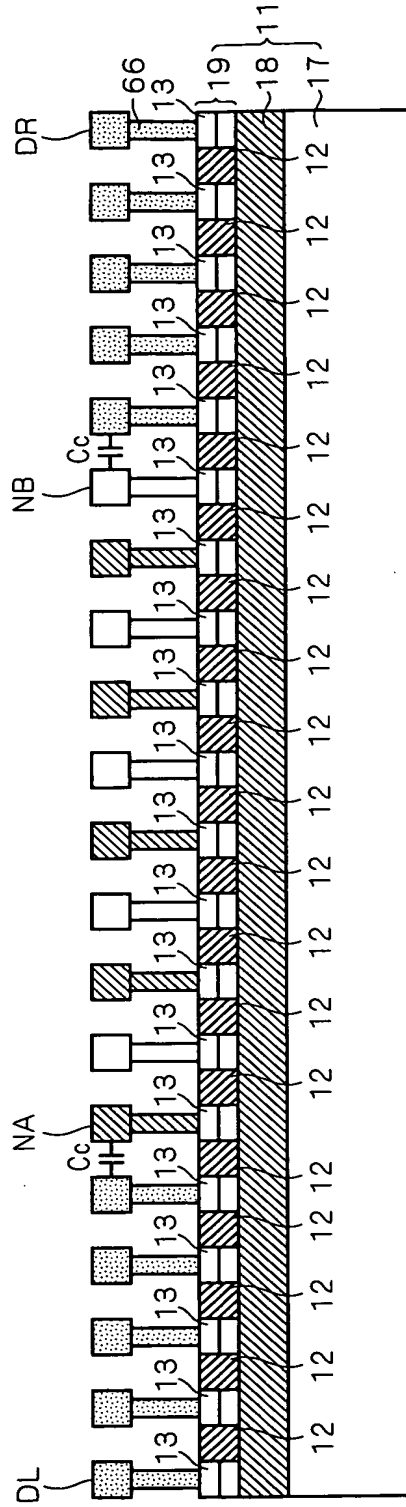
SEL=1  
(NB=NB)



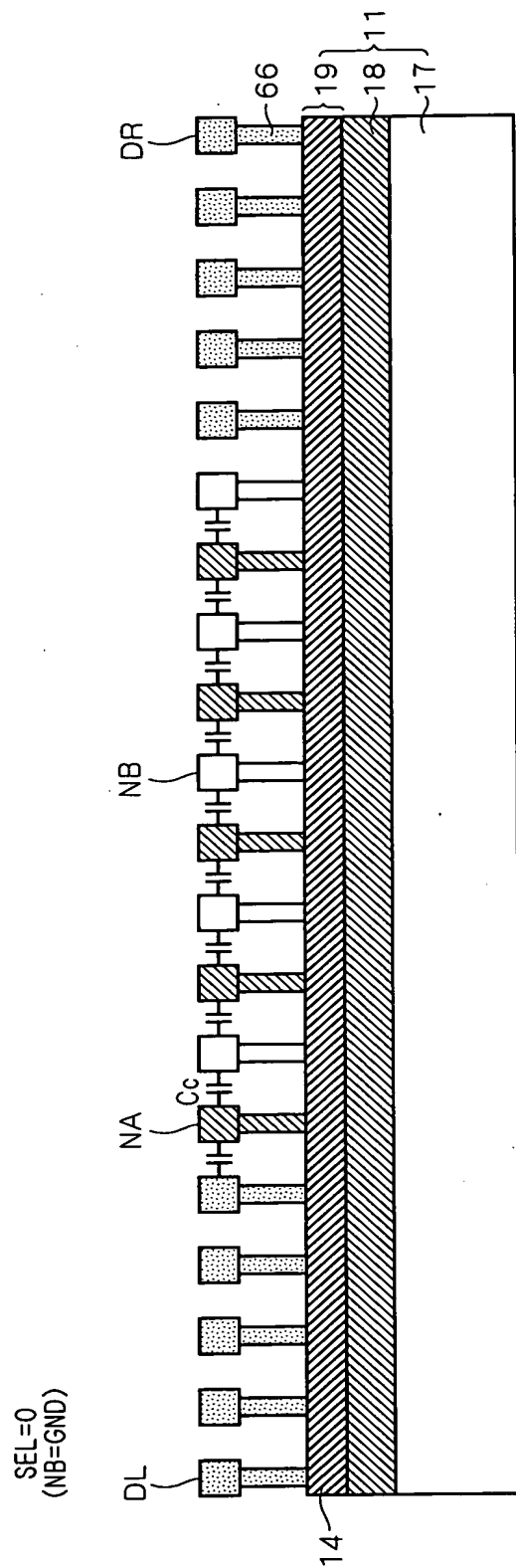
This diagram shows a cross-sectional view of a semiconductor device. The structure consists of several layers and regions. At the top, there are regions labeled DL, NA, CC, NB, and DR. Below these are various layers and regions labeled with numbers: 13, 12, 11, 17, 18, 19, and 66. A central region is labeled C<sub>sti</sub>. The diagram illustrates the complex layering and doping of the device.

F I G . 4 7

SEL=1  
(NB=NB)



F I G . 4 8

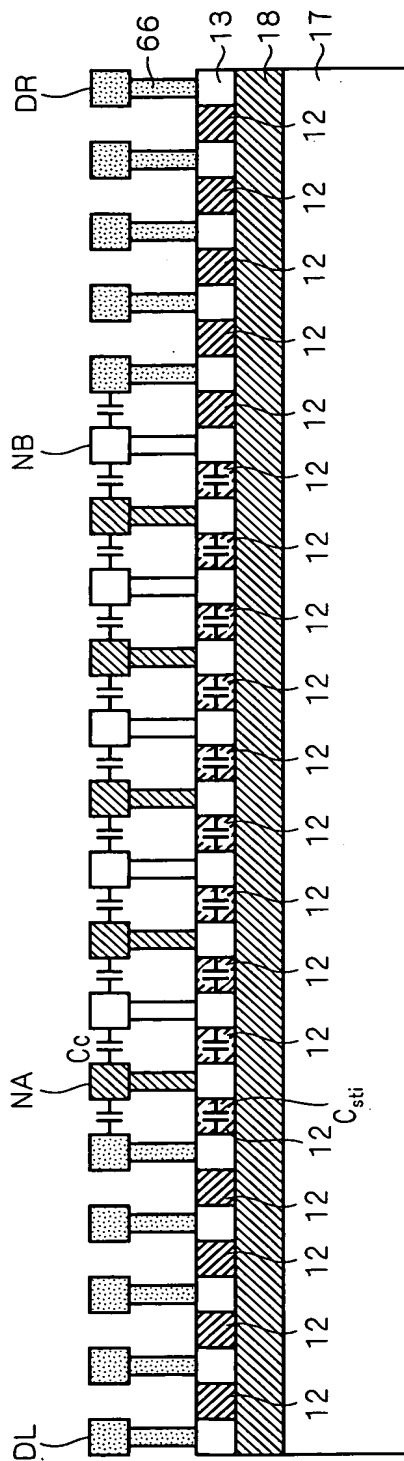






F I G . 5 0

SEL=0  
(NB=GND)



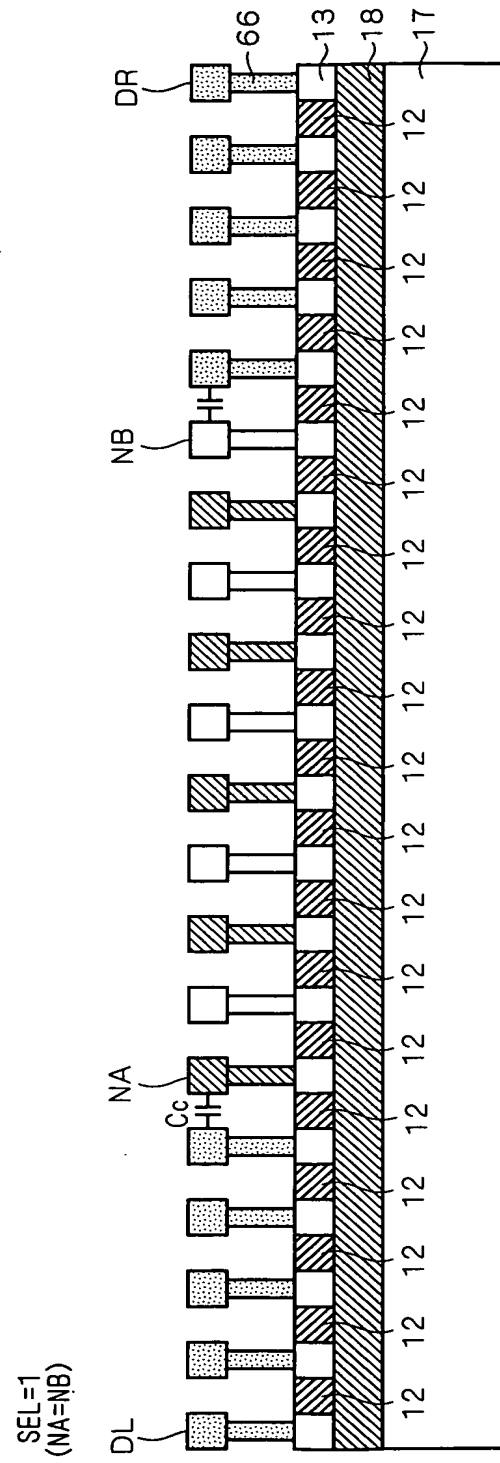
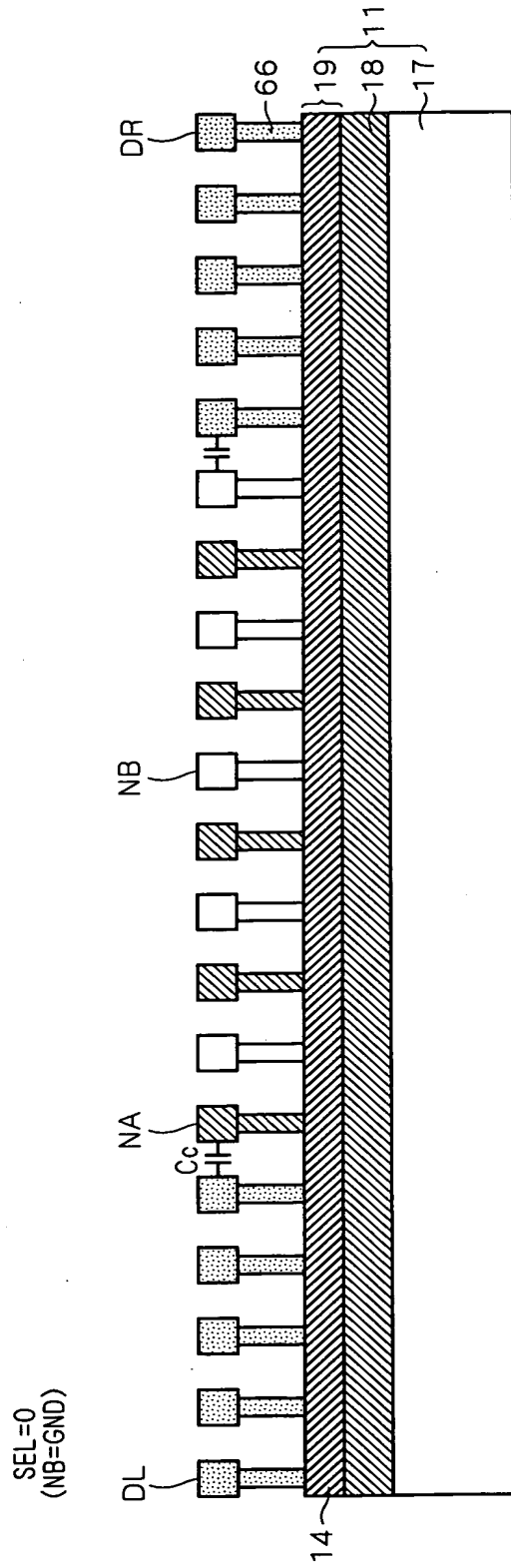
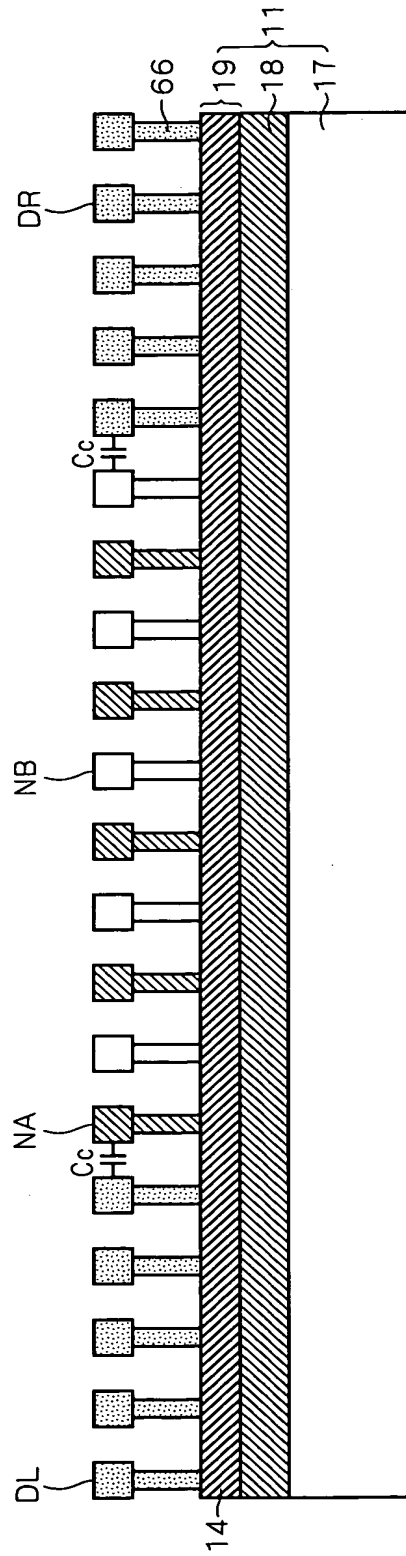


FIG. 52



35616

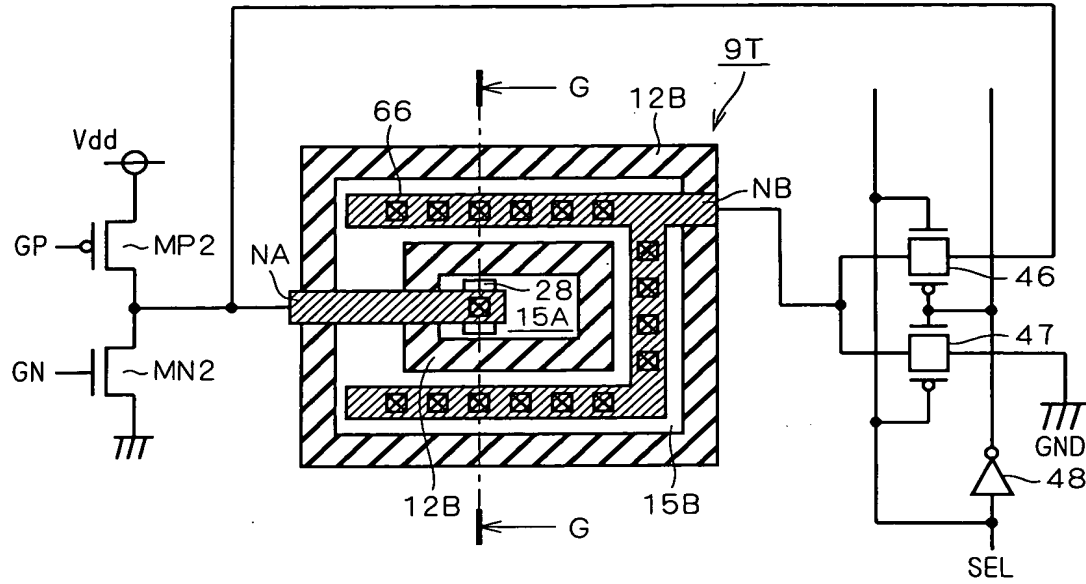
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SEL=1
(NB=NB)
```



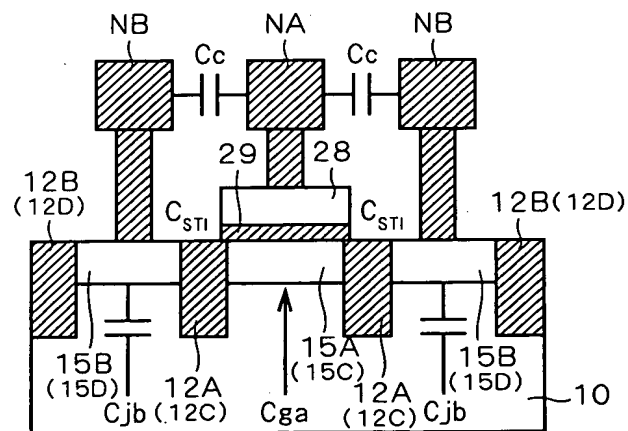




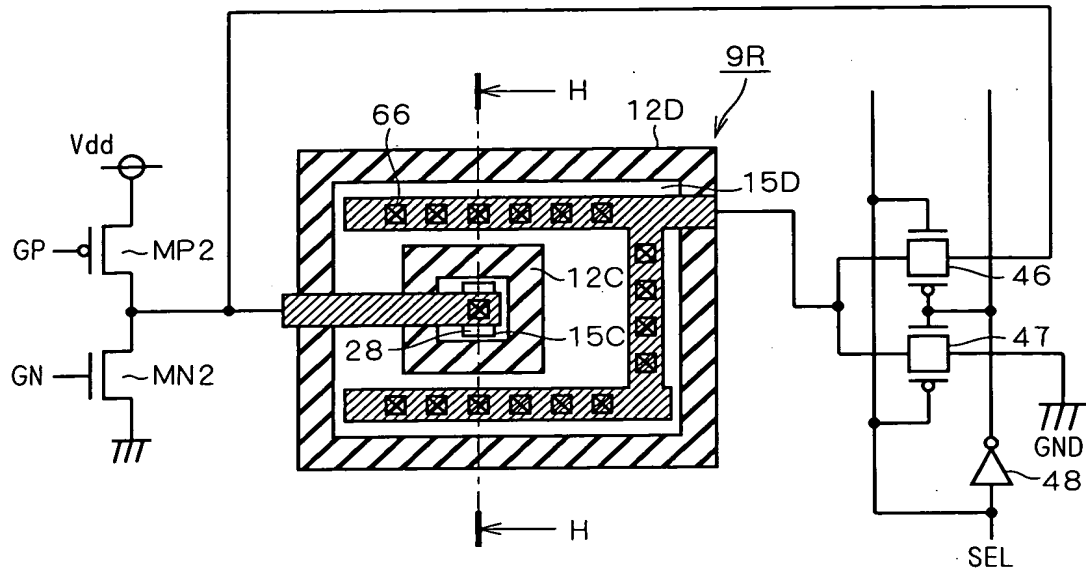
F I G . 5 7



F I G . 5 8

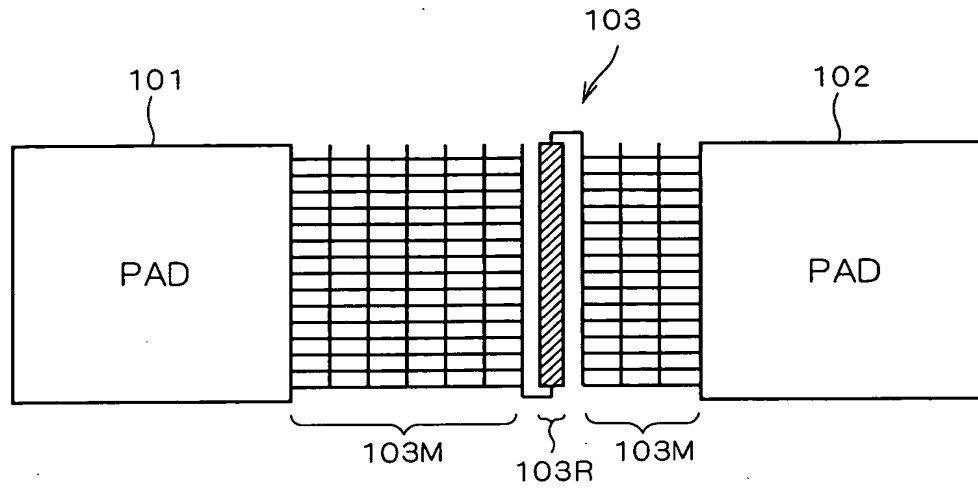


F I G . 5 9

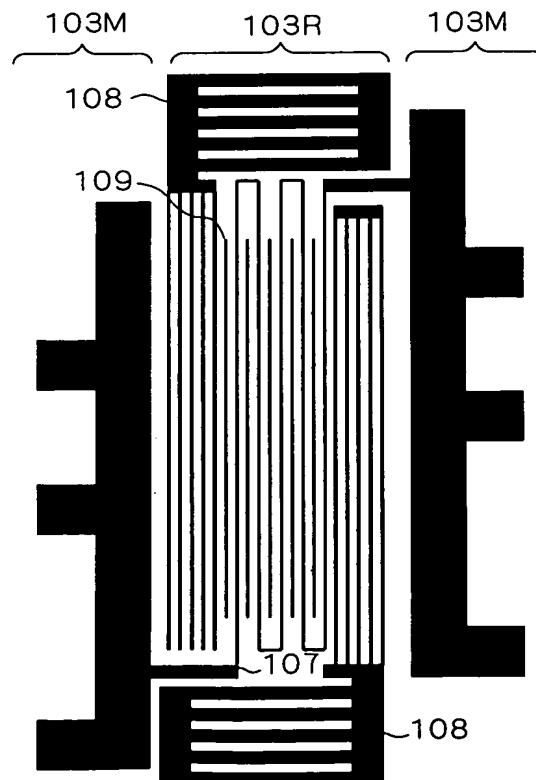




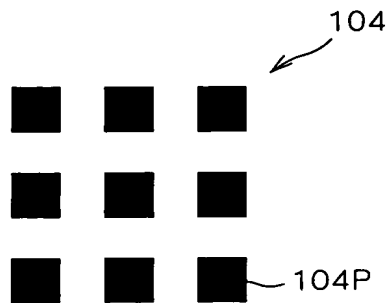
F I G . 6 0



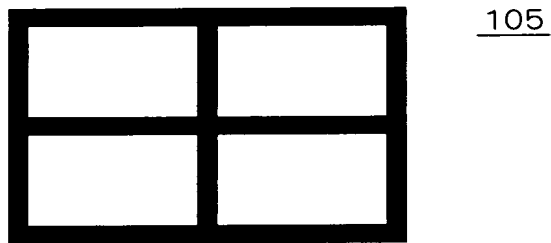
F I G . 6 1



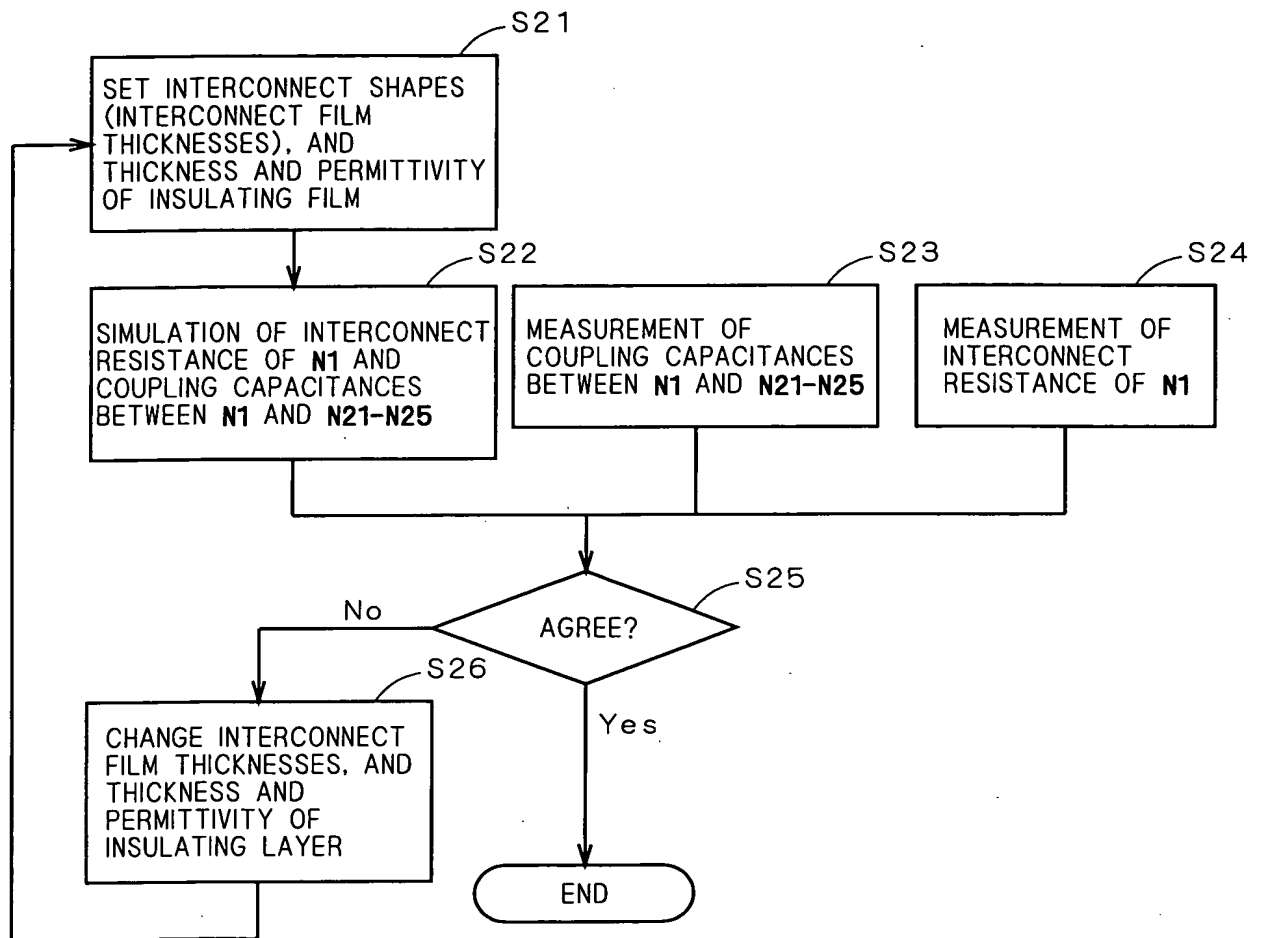
F I G . 6 2



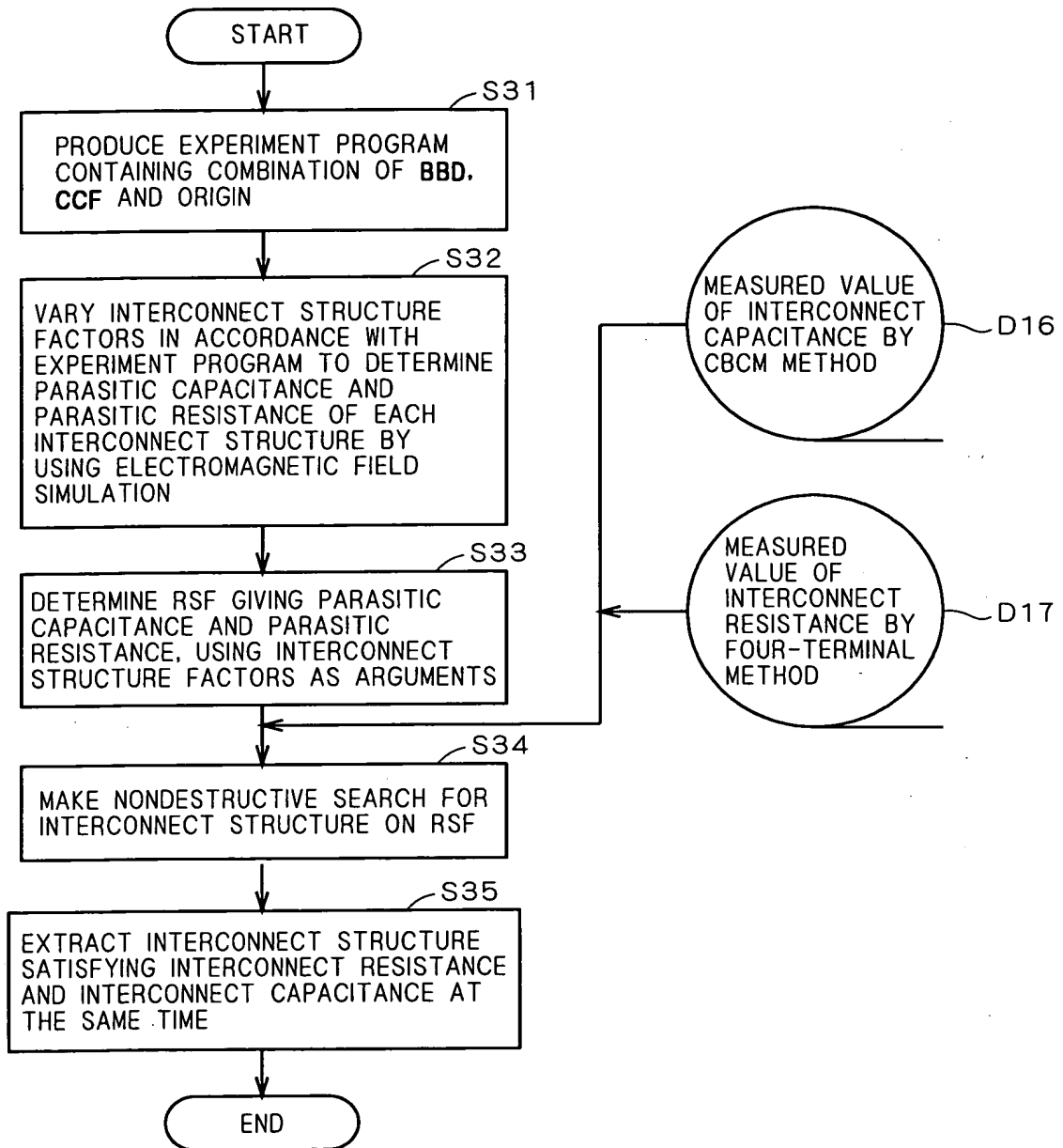
F I G . 6 3



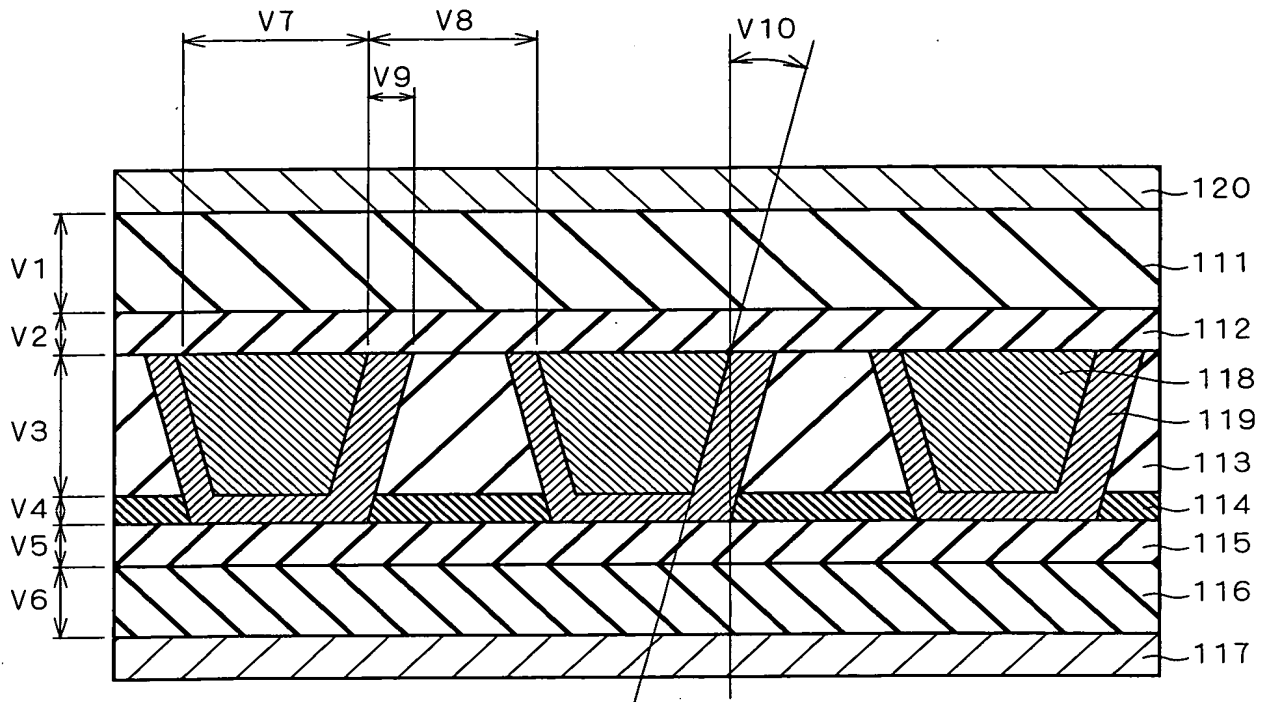
F I G . 6 4



F I G . 6 5



F I G . 6 6



[illegible]

F I G . 6 8

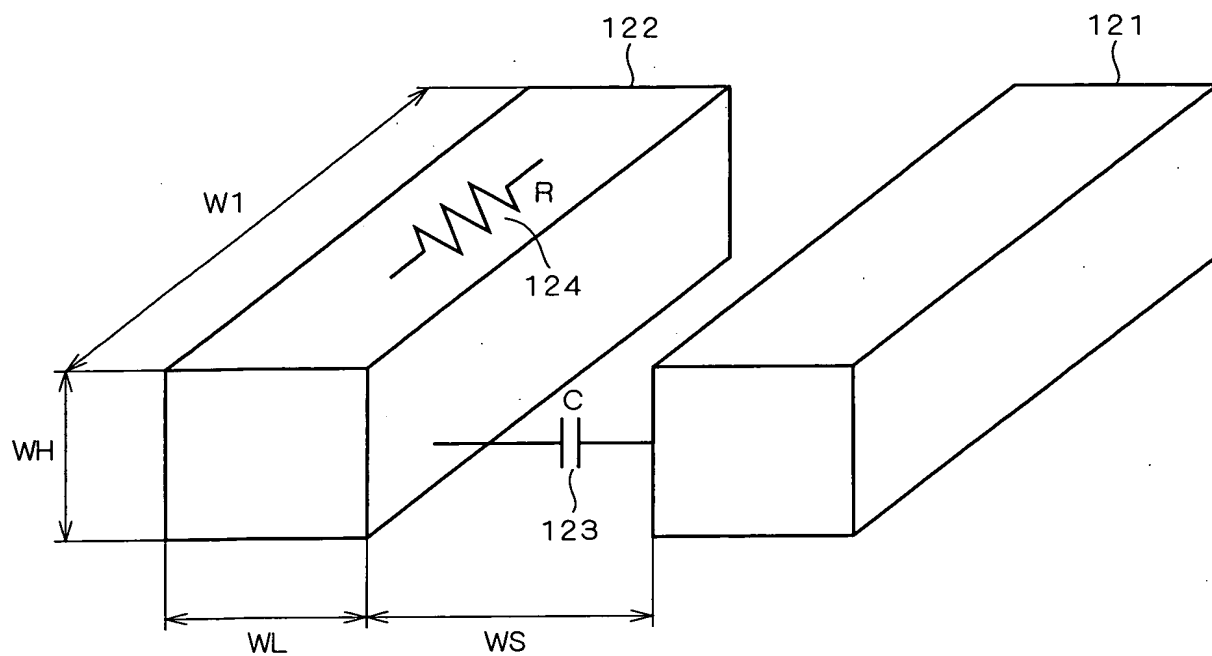






FIG. 70

